







LP875701-Q1

ZHCSJ52A - DECEMBER 2019 - REVISED AUGUST 2021

# 具有集成开关的 LP875701-Q1 四相、3MHz、1V、10A 直流/直流降压转换器

# 1 特性

- 符合汽车应用要求
- 具有符合 AEC-Q100 标准的下列特性:
  - 器件温度等级 1: -40°C 至 +125°C 环境工作 温度范围
  - 器件 HBM ESD 分类等级 2
  - 器件 CDM ESD 分类等级 C4B
- 输入电压: 2.8V 至 5.5V
- 输出电压: 1.0V
- 四个高效降压直流/直流转换器内核:
  - 最大输出电流:10A(2.5A/相)
- 开关频率: 3MHz
- 扩频模式和相位交错
- 可配置通用 I/O (GPIO)
- I<sup>2</sup>C 兼容接口,支持标准 (100kHz)、快速 (400kHz)、快速+ (1MHz) 和高速 (3.4MHz) 模式
- 具有可编程屏蔽的中断功能
- 可编程电源正常信号 (PGOOD)
- 输出短路和过载保护
- 过热警告和保护
- 过压保护 (OVP) 和欠压锁定 (UVLO)

# 2 应用

- 汽车信息娱乐系统
- 仪表组
- 雷达
- 摄像头电源应用

# 3 说明

LP875701-Q1 器件旨在满足各种汽车电源应用中新型 处理器和平台的电源管理要求。该器件包含 4 个降压 直流/直流转换器内核,这些内核配置为采用强制 PWM 模式的四相输出。该器件由 I2C 兼容串行接口和使能信 号进行控制。

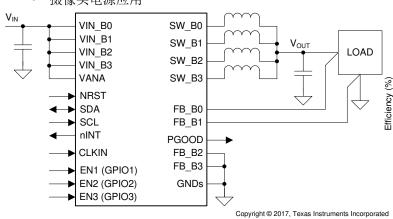
LP875701-Q1 支持对多相位输出的远程差分电压感 应,可补偿稳压器输出与负载点 (POL) 之间的 IR 压 降,从而提高输出电压的精度。可以强制开关时钟进入 PWM 模式并将其与外部时钟同步,从而更大程度地降 低干扰。

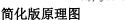
LP875701-Q1 器件支持负载电流测量,无需添加外部 电流感应电阻器。LP875701-Q1 器件还支持与使能信 号同步的可编程启动与关断延迟和序列。这些序列可能 还包括用于控制外部稳压器、负载开关和处理器复位的 GPIO 信号。在启动期间,该器件会对输出压摆率进行 控制,从而最大限度地减小输出电压过冲和浪涌电流。

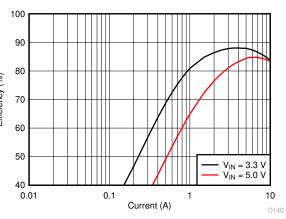
#### 器件信息(1)

器件型号	封装	封装尺寸(标称值)
LP875701-Q1	VQFN-HR (26)	4.50mm × 4.00mm

如需了解所有可用封装,请参阅数据表末尾的可订购产品附 录。







效率与输出电流间的关系



# **Table of Contents**

1 特性	1	7.5 Programming	31
. · · · 2 应用		7.6 Register Maps	
- <i>—,,,,</i> 3 说明		8 Application and Implementation	<mark>5</mark> 6
4 Revision History		8.1 Application Information	<u>5</u> 6
5 Pin Configuration and Functions		8.2 Typical Application	56
6 Specifications		9 Power Supply Recommendations	61
6.1 Absolute Maximum Ratings		10 Layout	62
6.2 ESD Ratings		10.1 Layout Guidelines	62
6.3 Recommended Operating Conditions		10.2 Layout Example	63
6.4 Thermal Information		11 Device and Documentation Support	64
6.5 Electrical Characteristics		11.1 接收文档更新通知	6 <sup>4</sup>
6.6 I <sup>2</sup> C Serial Bus Timing Requirements		11.2 支持资源	64
6.7 Typical Characteristics		11.3 Trademarks	64
7 Detailed Description		11.4 Electrostatic Discharge Caution	64
7.1 Overview		11.5 术语表	<u>6</u> 4
7.2 Functional Block Diagram		12 Mechanical, Packaging, and Orderable	
7.3 Feature Descriptions		Information	64
7.4 Device Functional Modes			

4 Revision History 注:以前版本的页码可能与当前版本的页码不同

CI	nanges from Revision *	(December 2019) to Revision A (August 2021)	Page
•	更新了整个文档中的表、	图和交叉参考的编号格式	1



# **5 Pin Configuration and Functions**

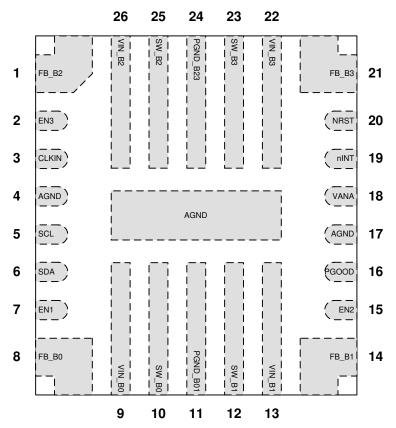


图 5-1. RNF Package 26-Pin VQFN-HR With Thermal Pad Top View

表 5-1. Pin Functions

PIN		TYPE(1)	DESCRIPTION
NO.	NAME	ITPE	DESCRIPTION
1	FB_B2	А	Output voltage feedback (positive) for the BUCK2 converter.
2	EN3	D/I/O	Programmable enable signal for the buck regulators (can be also configured to select between two buck output-voltage levels). This pin functions alternatively as GPIO3.
3	CLKIN	D/I	External clock input. Connect this pin to ground if the external clock is not used.
4, 17, Thermal Pad	AGND	G	Ground
5	SCL	D/I	Serial interface clock input for I <sup>2</sup> C access. Connect this pin to a pullup resistor.
6	SDA	D/I/O	Serial interface data input and output for I <sup>2</sup> C access. Connect this pin to a pullup resistor.
7	EN1	D/I/O	Programmable enable signal for the buck regulators (can be also configured to select between two buck output voltage levels). This pin functions alternatively as GPIO1.
8	FB_B0	А	Output voltage feedback (positive) for the BUCK0 converter.
9	VIN_B0	Р	Input for the BUCK0 converter. The separate power pins, VIN_Bx, are not connected together internally. The VIN_Bx pins must be connected together in the application and be locally bypassed.
10	SW_B0	А	BUCK0 switch node
11	PGND_B01	G	Power ground for the BUCK0 and BUCK1 converters
12	SW_B1	Α	BUCK1 switch node
13	VIN_B1	Р	Input for the BUCK1 converter. The separate power pins, VIN_Bx, are not connected together internally. The VIN_Bx pins must be connected together in the application and be locally bypassed.



# 表 5-1. Pin Functions (continued)

PIN		TYPE(1)	DESCRIPTION	
NO.	NAME	ITPE	DESCRIPTION	
14	FB_B1	А	Output voltage feedback (positive) for the BUCK1 converter. This pin functions alternatively as the output ground feedback (negative) for the BUCK0 converter.	
15	EN2	D/I/O	grammable enable signal for the buck regulators (can be also configured to select between buck output voltage levels). This pin functions alternatively as GPIO2.	
16	PGOOD	D/O	ver-good indication signal	
18	VANA	Р	Supply voltage for the analog and digital blocks. This pin must be connected to the same node as VIN_Bx.	
19	nINT	D/O	en-drain interrupt output. This pin is active low.	
20	NRST	D/I	Reset signal for the device	
21	FB_B3	А	Output voltage feedback (positive) for the BUCK3 converter. This pin functions alternatively as the output ground feedback (negative) for the BUCK2 converter.	
22	VIN_B3	Р	Input for the BUCK3 converter. The separate power pins, VIN_Bx, are not connected together internally. The VIN_Bx pins must be connected together in the application and be locally bypassed.	
23	SW_B3	Α	BUCK3 switch node	
24	PGND_B23	G	Power ground for the BUCK2 and BUCK3 converters	
25	SW_B2	Α	BUCK2 switch node	
26	VIN_B2	Р	Input for the BUCK2 converter. The separate power pins, VIN_Bx, are not connected together internally. The VIN_Bx pins must be connected together in the application and be locally bypassed.	

(1) A: Analog Pin, D: Digital Pin, G: Ground Pin, P: Power Pin, I: Input Pin, O: Output Pin

# **6 Specifications**

# **6.1 Absolute Maximum Ratings**

Over operating free-air temperature range (unless otherwise noted)(1) (2)

		MIN	MAX	UNIT
Voltage on power connections	VIN_Bx, VANA	- 0.3	6	V
Voltage on buck switch nodes	SW_Bx	- 0.3	(VIN_Bx + 0.3 V) with 6 V maximum	V
Voltage on buck voltage sense nodes	FB_Bx	- 0.3	(VANA + 0.3 V) with 6 V maximum	V
Voltage on NRST input	NRST	- 0.3	6	V
	SDA, SCL, nINT, CLKIN	- 0.3	6	V
Voltage on logic pins (input or output pins)	EN1 (GPIO1), EN2 (GPIO2), EN3 (GPIO3), PGOOD	- 0.3	(VANA + 0.3 V) with 6 V maximum	V
Maximum lead temperature (soldering, 10 sec.)	·		260	°C
Junction temperature, T <sub>J-MAX</sub>		- 40	150	°C
Storage temperature, T <sub>stg</sub>		- 65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# 6.2 ESD Ratings

				VALUE	UNIT
V/ECD)		Human-body model (HBM), per AEC Q100-002 <sup>(1)</sup>		±2000	
	Electrostatic discharge	Charged-device model (CDM), per AEC Q100-011	All pins	±500	V
		Charged-device moder (CDIVI), per ALC Q100-011	Corner pins (1, 8, 14, and 21)	±750	

<sup>(1)</sup> AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

# **6.3 Recommended Operating Conditions**

Over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
INPUT VOLTAGE				
Voltage on power connections	VIN_Bx, VANA	2.8	5.5	V
Voltage on NRST	NRST	1.65	VANA with 5.5 V maximum	V
Voltage on logic pins (input or output pins)	nINT, CLKIN	1.65	5.5	V
Voltage on logic pins (input or output pins)	ENx, PGOOD	0	VANA with 5.5 V maximum	V
Voltage on I <sup>2</sup> C interface, standard (100 kHz), fast (400 khz), fast+ (1 MHz), and high-speed (3.4 MHz) modes	SCL, SDA	1.65	1.95	V
Voltage on I <sup>2</sup> C interface, standard (100 kHz), fast (400 kHz), and fast+ (1 MHz) modes	SCL, SDA	3.1	VANA with 3.6 V maximum	V
TEMPERATURE		•		
Junction temperature, T <sub>J</sub>		- 40	140	°C
Ambient temperature, T <sub>A</sub>		- 40	125	°C

<sup>(2)</sup> All voltage values are with respect to network ground.



## **6.4 Thermal Information**

		LP875701-Q1	
	THERMAL METRIC <sup>(1)</sup> 26 PINS  A Junction-to-ambient thermal resistance 34.6  C(top) Junction-to-case (top) thermal resistance 16.5  Junction-to-board thermal resistance 4.7  Junction-to-top characterization parameter 0.6  Junction-to-board characterization parameter 4.7	UNIT	
		26 PINS	
R <sub>0</sub> JA	Junction-to-ambient thermal resistance	34.6	°C/W
R <sub>θ JC(top)</sub>	Junction-to-case (top) thermal resistance	16.5	°C/W
R <sub>0</sub> JB	Junction-to-board thermal resistance	4.7	°C/W
ψJT	Junction-to-top characterization parameter	0.6	°C/W
ψ ЈВ	Junction-to-board characterization parameter	4.7	°C/W
R <sub>θ JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	1.4	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

#### 6.5 Electrical Characteristics

 $-40^{\circ}C\leqslant T_{J}\leqslant +140^{\circ}C,\ C_{POL}=122\ \mu\text{F/phase, specified }V_{VANA},\ V_{VIN\_Bx}\ ,\ V_{NRST},\ V_{VOUT\_Bx},\ \text{and }I_{OUT}\ \text{range, unless otherwise noted.}$  noted. Typical values are at  $T_{J}=25^{\circ}C,\ V_{VANA}=V_{VIN\_Bx}=3.7\ V,\ \text{and}\ V_{OUT}=1.0\ V,\ \text{unless otherwise noted.}^{(1)}$ 

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
EXTERNAL	COMPONENTS					
C <sub>IN</sub>	Input filtering capacitance	Connected from VIN_Bx to PGND_Bx	1.9	10		μF
C <sub>OUT</sub>	Output filtering capacitance per phase, local		10	22		μF
C <sub>POL</sub>	Point-of-load (POL) capacitance per phase			122		μF
C <sub>OUT-TOTAL</sub>	Total output capacitance <sup>(2)</sup> (local and POL)	4-phase output	400		1500	μF
ESR <sub>C</sub>	ESR of the input and output capacitor	1 MHz $\leqslant$ f $\leqslant$ 10 MHz		2	10	mΩ
	Inductor value and			0.33		μH
L	tolerance of the inductor		- 30%		30%	
DCRL	Inductor DCR			20		mΩ
BUCK REG	ULATOR					
V <sub>VIN_Bx</sub>	Input voltage range		2.8		5.5	V
	Output current <sup>(3)</sup> The	4-phase output, V <sub>IN</sub> ≥ 3 V			10	
I <sub>OUT</sub>	maximum output current from device is 10A regardless of device phase configurations.	4-phase output, 2.8 V $\leq$ V <sub>IN</sub> < 3 V			7.2	A
	Input and output voltage difference Minimum voltage between VIN_x and V <sub>OUT</sub> to fulfill the electrical characteristics		0.5			V
V <sub>VOUT_DC</sub>	DC output voltage and accuracy, includes voltage reference, DC load and line regulations, process, and temperature	$V_{\text{IN}}\!=\!3.3~\text{V}$ +/- 5% , 5 V +/- 5%, forced PWM mode, forced 4-phase operation, $f_{\text{SW}}\!=\!3$ MHz +/- 10% (either through internal or external clock), in case external clock is used: spread-spectrum disabled	0.985	1	1.015	V
	Ripple voltage	4-phase output, forced PWM mode, ESR <sub>C</sub> < 2 m $\Omega$ , L = 0.33 $\mu$ H		3		mV <sub>p-p</sub>
DC <sub>LNR</sub>	DC line regulation	I <sub>OUT</sub> = I <sub>OUT(max)</sub>		0.1		%/V
$DC_{LDR}$	DC load regulation in PWM mode	$0 \text{ A} \leqslant I_{\text{OUT}} \leqslant I_{\text{OUT(max)}}$		0.01		%/A

# **6.5 Electrical Characteristics (continued)**

 $^-$  40°C  $\leq$  T<sub>J</sub>  $\leq$  +140°C, C<sub>POL</sub> = 122 μF/phase, specified V<sub>VANA</sub>, V<sub>VIN\_Bx</sub>, V<sub>NRST</sub>, V<sub>VOUT\_Bx</sub>, and I<sub>OUT</sub> range, unless otherwise noted. Typical values are at T<sub>J</sub> = 25°C, V<sub>VANA</sub> = V<sub>VIN\_Bx</sub> = 3.7 V, and V<sub>OUT</sub> = 1.0 V, unless otherwise noted. (1)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
TD	Transient load step	$V_{IN}$ = 5 V +/- 5%, $f_{SW}$ = 3 MHz +/- 10% (either through internal or external clock), in case external clock is used: spread-spectrum disabled, forced 4-phase operation, forced PWM mode 1.5 A $\leq$ I <sub>OUT</sub> $\leq$ 7.5 A, $t_r$ = $t_f$ = 1 μs, $C_{OUT}$ = 22 μF/phase, L = 0.33 μH, $C_{POL}$ = 122 μF/ phase		±12		m\/
TR <sub>LDSR</sub>	response in PWM mode	$V_{IN}$ = 3.3 V +/- 5%, $f_{SW}$ = 3 MHz +/- 10% (either through internal or external clock), in case external clock is used: spread-spectrum disabled, forced 4-phase operation, forced PWM mode 1.5 A $\leq$ I <sub>OUT</sub> $\leq$ 7.5 A, $t_r$ = $t_f$ = 1 μs, $C_{OUT}$ = 22 μF/phase, L = 0.33 μH, $C_{POL}$ = 122 μF/phase		±15		mV
TR <sub>LNSR</sub>	Transient line response	$V_{VIN\_Bx}$ stepping 3.15 V $\leftrightarrow$ 3.4 V, $t_r$ = $t_f$ = 10 $\mu$ s, $I_{OUT}$ = $I_{OUT(max)}$		±2		mV
l	Forward current limit for	$V_{VIN\_Bx} \geqslant 3 \text{ V}$ Forward current limit for each phase set to 3.5A (ILIMx[2:0]=4h)	3.3	3.8	4.2	Δ
'LIM FWD	each phase (peak for each switching cycle)	$2.8~V \leqslant V_{VIN\_Bx} < 3~V$ Forward current limit for each phase set to $3.5A~(ILIMx[2:0]=4h)$	2.8	3.8	4.2	A
I <sub>LIM NEG</sub>	Negative current limit per phase (peak for each switching cycle)		1.6	2	2.4	А
R <sub>DS(ON)</sub> HS FET	On-resistance, high-side FET	Each phase, between VIN_Bx and SW_Bx pins, I = 1 A		29	65	mΩ
R <sub>DS(ON) LS</sub> FET	On-resistance, low-side FET	Each phase, between SW_Bx and PGND_Bx pins, I = 1 A		17	35	mΩ
$f_{SW}$	Switching frequency, PWM mode		2.7	3	3.3	MHz
	Current balancing for multiphase outputs	Current mismatch between phases, I <sub>OUT</sub> > 1 A/phase			10%	
	Start-Up time (soft start)	From ENx to $V_{OUT}$ = 0.35 V (slew-rate control begins), $C_{OUT\_TOTAL}$ = 144 $\mu$ F/phase		200		μs
	Output voltage slew-rate <sup>(4)</sup>		3.23	3.8	4.4	mV/μ
	Output pulldown resistance	Regulator disabled	160	230	300	Ω
		Overvoltage monitoring (compared to DC output-voltage level, V <sub>VOUT_DC</sub> )	39	50	64	mV
		Undervoltage monitoring (compared to DC output-voltage level, V <sub>VOUT_DC</sub> )	- 53	- 40	- 29	1117
	Output voltage monitoring for PGOOD pin	Deglitch time during regulator enable PGOOD_SET_DELAY = 0h	4	7	10	μs
		Deglitch time during regulator enable PGOOD_SET_DELAY = 1h	10	11	13	ms
		Deglitch time during operation and after voltage change	4	7	10	μs
	Power-good threshold for interrupt BUCKx_PG_INT,	Rising ramp voltage, enable or voltage change	- 20	- 14	- 8	mV
	difference from final voltage	Falling ramp voltage, voltage change	8	14	20	



# 6.5 Electrical Characteristics (continued)

-40°C  $\leq$  T<sub>J</sub>  $\leq$  +140°C, C<sub>POL</sub> = 122 μF/phase, specified V<sub>VANA</sub>, V<sub>VIN\_Bx</sub>, V<sub>NRST</sub>, V<sub>VOUT\_Bx</sub>, and I<sub>OUT</sub> range, unless otherwise noted. Typical values are at T<sub>J</sub> = 25°C, V<sub>VANA</sub> = V<sub>VIN\_Bx</sub> = 3.7 V, and V<sub>OUT</sub> = 1.0 V, unless otherwise noted. (1)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Power-good threshold for status bit BUCKx_PG_STAT	During operation, status signal is forced to 0h during voltage change	- 20	- 14	- 8	mV
EXTERNAL	CLOCK AND PLL					
	Nominal frequency of the external input clock		1		24	MHz
	Nominal frequency step size of the external input clock			1		MHz
	Required accuracy from nominal frequency of the external input clock		- 30%		10%	
	Delay time for missing external clock detection				1.8	μs
	Delay and debounce time for external clock detection				20	μs
	Clock change delay (internal to external) delay from valid clock detection to use of external clock			600		μs
	Cycle-to-cycle PLL output clock jitter			300		ps, p-
PROTECTI	ON FUNCTIONS					
	clock jitter  ION FUNCTIONS  Thermal warning  Thermal warning	Temperature rising, TDIE_WARN_LEVEL = 0h	115	125	135	°C
		Temperature rising, TDIE_WARN_LEVEL = 1h	127	137	147	0
	Thermal warning hysteresis			20		°C
	Thermal shutdown	Temperature rising	140	150	160	°C
	Thermal shutdown hysteresis			20		°C
VANA <sub>OVP</sub>	VANA overvoltage	Voltage rising	5.6	5.8	20  135  147  147  160  160  183  5.96  20.47	V
		Voltage falling	5.45	5.73	5.96	
	VANA overvoltage hysteresis		40			mV
VANA <sub>UVLO</sub>	VANA undervoltage	Voltage rising	2.51	2.63	2.75	V
AYI AYUNTO	lockout	Voltage falling	2.5	2.6	2.7	•
LOAD CUR	RENT MEASUREMENT					
	Current measurement range	Output current for maximum code			20.47	А
	Resolution	LSB		20		mA
	Measurement accuracy	I <sub>OUT</sub> > 1 A		<10%		
	Measurement time	PWM mode		4		μs
CURRENT	CONSUMPTION	1 L				I
	Shutdown current consumption	From VANA and VIN_Bx pins, NRST = 0 V, VANA = VIN_Bx = 3.7 V		1.4		μA
	Standby current consumption	From VANA and VIN_Bx pins, NRST = 1.8 V, VANA = VIN_Bx = 3.7 V, regulators disabled		6.7		μA

# 6.5 Electrical Characteristics (continued)

 $^-$  40°C ≤ T<sub>J</sub> ≤ +140°C, C<sub>POL</sub> = 122 μF/phase, specified V<sub>VANA</sub>, V<sub>VIN\_Bx</sub> , V<sub>NRST</sub>, V<sub>VOUT\_Bx</sub>, and I<sub>OUT</sub> range, unless otherwise noted. Typical values are at T<sub>J</sub> = 25°C, V<sub>VANA</sub> = V<sub>VIN\_Bx</sub> = 3.7 V, and V<sub>OUT</sub> = 1.0 V, unless otherwise noted. (1)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Active current consumption	Total current for forced 4-phase operation, $V_{\text{IN}} = 3.3 \text{ V}$		70		mA
	during PWM operation	Total current for forced 4-phase operation, $V_{\text{IN}} = 5 \text{ V}$		103		ША
	PLL and clock detector current consumption	Additional current consumption when internal RC oscillator, clock detector and PLL are enabled		2		mA
DIGITAL	. INPUT SIGNALS: NRST, EN1,	EN2, EN3, EN4, SCL, SDA, GPIO1, GPIO2,	GPIO3, CLKIN			
V <sub>IL</sub>	Input low level				0.4	V
V <sub>IH</sub>	Input high level		1.2			V
V <sub>HYS</sub>	Hysteresis of Schmitt trigger inputs		10	77	200	mV
	ENx pulldown resistance	ENx_PD = 1h		500		kΩ
	NRST pulldown resistance	Always present	650	1150	1700	kΩ
DIGITAL	OUTPUT SIGNALS: nINT		1		-	
V <sub>OL</sub>	Output low level	I <sub>SOURCE</sub> = 2 mA			0.4	V
R <sub>P</sub>	External pullup resistor	To VIO supply		10		kΩ
DIGITAL	OUTPUT SIGNALS: SDA					
V <sub>OL</sub>	Output low level	I <sub>SOURCE</sub> = 10 mA			0.4	V
DIGITAL	OUTPUT SIGNALS: PGOOD,	GPIO1, GPIO2, GPIO3				
V <sub>OL</sub>	Output low level	I <sub>SOURCE</sub> = 2 mA			0.4	V
V <sub>OH</sub>	Output high level, configured to push-pull	I <sub>SINK</sub> = 2 mA	V <sub>VANA</sub> - 0.4		$V_{VANA}$	V
$V_{PU}$	Supply voltage for external pull-up resistor, configured to open-drain				$V_{VANA}$	V
R <sub>PU</sub>	External pullup resistor, configured to open-drain			10		kΩ
ALL DIG	SITAL INPUTS					
I <sub>LEAK</sub>	Input current	All logic inputs over pin voltage range (except NRST)	-1		1	μA

<sup>(1)</sup> All voltage values are with respect to network ground.

<sup>(2)</sup> The output voltage slew-rate setting limits the maximum output capacitance.

<sup>(3)</sup> The maximum output current can be limited by the forward current limit I<sub>LIM FWD</sub> and by the junction temperature. The power dissipation inside the die depends on the length of the current pulse and efficiency and the junction temperature may increase to thermal shutdown level if the board and ambient temperatures are high.

<sup>(4)</sup> Output capacitance, forward and negative current limits and load current may limit the maximum and minimum slew rates.



# 6.6 I<sup>2</sup>C Serial Bus Timing Requirements

These specifications are ensured by design.  $V_{IN\ Bx}$  = 3.7 V, unless otherwise noted.

			MIN	MAX	UNIT	
		Standard mode		100	kHz	
		Fast mode		400	IXI IZ	
SCL	Serial clock frequency	Fast mode+		1		
		High-speed mode, C <sub>b</sub> = 100 pF		3.4	MHz	
		High-speed mode, C <sub>b</sub> = 400 pF		1.7		
		Standard mode	4.7			
		Fast mode	1.3		μs	
LOW	SCL low time	Fast mode+	0.5			
		High-speed mode, C <sub>b</sub> = 100 pF	160			
		High-speed mode, C <sub>b</sub> = 400 pF	320		ns	
		Standard mode	4			
		Fast mode	0.6		μs	
HIGH	SCL high time	Fast mode+	0.26		40	
	· ·	High-speed mode, C <sub>b</sub> = 100 pF	60			
		High-speed mode, C <sub>b</sub> = 400 pF	120		ns	
		Standard mode	250			
		Fast mode	100			
SU;DAT Data setup time	Data setup time	Fast mode+	50		ns	
		High-speed mode	10			
		Standard mode	10	3450		
<sub>HD:DAT</sub> Data hold time		Fast mode	10	900	ns	
	Data hold time	Fast mode+	10		110	
HD;DAI	Bata fiold time	High-speed mode, C <sub>b</sub> = 100 pF	10	70		
		High-speed mode, C <sub>b</sub> = 400 pF	10	150	ns	
		Standard mode	4.7	100		
	Octor for a day		0.6		116	
SU;STA	Setup time for a start or a repeated start condition	Fast mode+	0.26		μs	
		High-speed mode	160		ne	
		Standard mode	4		ns	
HD;STA	Hold time for a start or a repeated start condition	Fast mode	0.6		μs	
	start containen	Fast mode+	0.26			
		High-speed mode	160		ns	
	Bus free time between a stop and	Standard mode	4.7			
BUF	start condition	Fast mode	1.3		μs	
		Fast mode+	0.5			
		Standard mode	4			
SU;STO	Setup time for a stop condition	Fast mode	0.6		μs	
.,•		Fast mode+	0.26			
		High-speed mode	160		ns	
		Standard mode		1000		
		Fast mode	20	300		
rDA	Rise time of SDA signal	Fast mode+		120	ns	
		High-speed mode, C <sub>b</sub> = 100 pF	10	80		
		High-speed mode, C <sub>b</sub> = 400 pF	20	160		

These specifications are ensured by design.  $V_{IN\_Bx}$  = 3.7 V, unless otherwise noted.

			MIN	MAX	UNIT	
		Standard mode		300		
		Fast mode	20 × (V <sub>DD</sub> / 5.5 V)	300		
t <sub>fDA</sub> Fall time of SDA s	Fall time of SDA signal	Fast mode+	20 × (V <sub>DD</sub> / 5.5 V)	120	ns	
		High-speed mode, C <sub>b</sub> = 100 pF	10	80		
		High-speed mode, C <sub>b</sub> = 400 pF	30	160		
		Standard mode		1000		
		Fast mode	20	300		
$t_{rCL}$	Rise time of SCL signal	Fast mode+		120	ns	
		High-speed mode, C <sub>b</sub> = 100 pF	10	40		
		High-speed mode, C <sub>b</sub> = 400 pF	20	80		
	Rise time of SCL signal after a	High-speed mode, C <sub>b</sub> = 100 pF	10	80		
t <sub>rCL1</sub>	repeated start condition and after an acknowledge bit	High-speed mode, C <sub>b</sub> = 400 pF	20	160	ns	
		Standard mode		300		
		Fast mode	20 × (V <sub>DD</sub> / 5.5 V)	300		
t <sub>fCL</sub>	Fall time of a SCL signal	Fast mode+	20 × (V <sub>DD</sub> / 5.5 V)	120	ns	
		High-speed mode, C <sub>b</sub> = 100 pF	10	40		
		High-speed mode, C <sub>b</sub> = 400 pF	20	80		
C <sub>b</sub>	Capacitive load for each bus line (SCL and SDA)			400	pF	
	Pulse width of spike suppressed	Standard mode, fast mode and fast mode+		50		
t <sub>SP</sub>	(SCL and SDA spikes that are less than the indicated width are suppressed)	High-speed mode		10	ns	

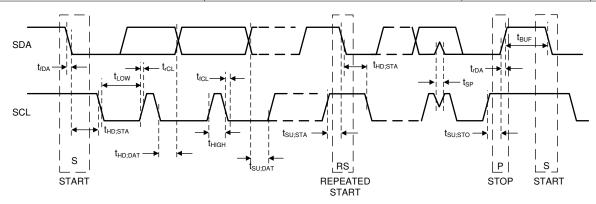
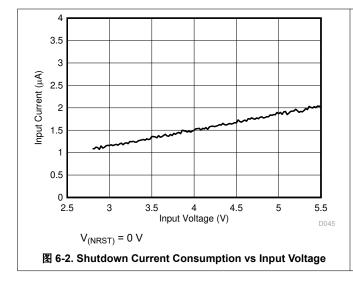


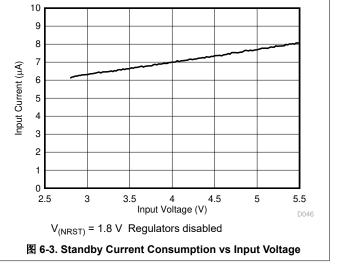
图 6-1. I<sup>2</sup>C Timing



# **6.7 Typical Characteristics**

Unless otherwise specified: T<sub>A</sub> = 25°C, V<sub>IN</sub> = 3.7 V, V<sub>OUT</sub> = 1 V, V<sub>(NRST)</sub> = 1.8 V,  $f_{SW}$  = 3 MHz, L = 0.33  $\mu$ H (Murata DFE252012PD-R33M), C<sub>OUT</sub> = 22  $\mu$ F / phase, C<sub>POL</sub> = 122  $\mu$ F / phase.







# 7 Detailed Description

## 7.1 Overview

TheLP875701-Q1 is a high-efficiency, high-performance power supply device with four step-down DC/DC converter cores for automotive applications. 表 7-1 lists the output characteristics of the regulators.

表 7-1. Regulator Outputs

SUPPLY	OUTPUT			
SUFFLI	V <sub>OUT</sub> RANGE	RESOLUTION	I <sub>MAX</sub> MAXIMUM OUTPUT CURRENT	
BUCK0, BUCK1, BUCK2, BUCK3 in one 4- phase output	1.0 V	Not Applicable	2.5 A per phase	

The LP875701-Q1 also supports switching clock synchronization to an external clock. The nominal frequency of the external clock can be from 1 MHz to 24 MHz with 1-MHz steps.

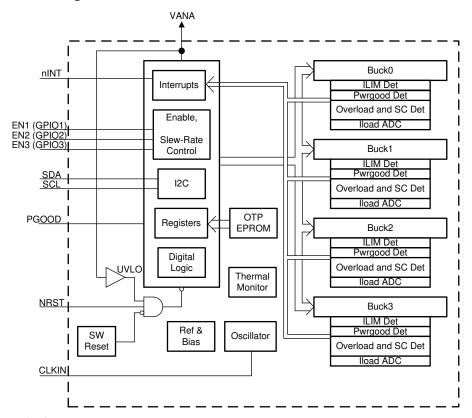
#### Additional features include:

- · Soft start
- Input voltage protection:
  - Undervoltage lockout
  - Overvoltage protection
- · Output voltage monitoring and protection:
  - Overvoltage monitoring
  - Undervoltage monitoring
  - Overload protection
- Thermal warning
- Thermal shutdown

Three enable signals can be multiplexed to general purpose I/O (GPIO) signals. The direction and output type (open-drain or push-pull) are programmable for the GPIOs.



#### 7.2 Functional Block Diagram



# 7.3 Feature Descriptions

#### 7.3.1 Multi-Phase DC/DC Converters

#### 7.3.1.1 Overview

The LP875701-Q1 includes four step-down DC/DC converter cores which are configured as a 4-phase single output.

TheLP875701-Q1 has the following features:

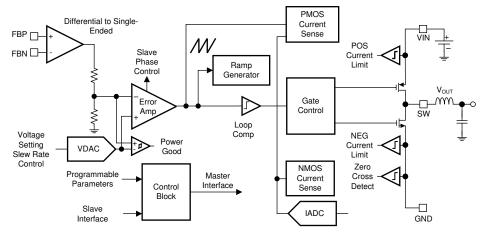
- Optional external clock input to minimize crosstalk
- · Optional spread spectrum technique to decrease EMI
- · Phase control for optimized EMI
- · Synchronous rectification
- Current mode loop with PI compensator
- · Soft start
- · Power Good flag with maskable interrupt
- · Power Good signal (PGOOD) with selectable sources
- Average output current sensing (for load current measurement)
- Current balancing between the phases of the converter
- · Differential voltage sensing from point of the load for multiphase output

The following parameters can be programmed via registers:

- Forced multiphase operation for multiphase outputs (forces also the PWM operation)
- Enable and disable delays for regulators and GPIOs controlled by ENx pins

The 4 buck converters in the LP875701-Q1 operate in forced multiphase configuration as one 4-phase converter, which offers several advantages over one power stage converter. For application processor power delivery, lower ripple on the input and output currents and faster transient response to load steps are the most significant advantages. Also, because the load current is evenly shared among multiple channels in multiphase output configuration, the heat generated is greatly decreased for each channel due to the fact that power loss is proportional to square of current. The physical size of the output inductor shrinks significantly due to this heat reduction. 87-1 shows a block diagram of a single core.

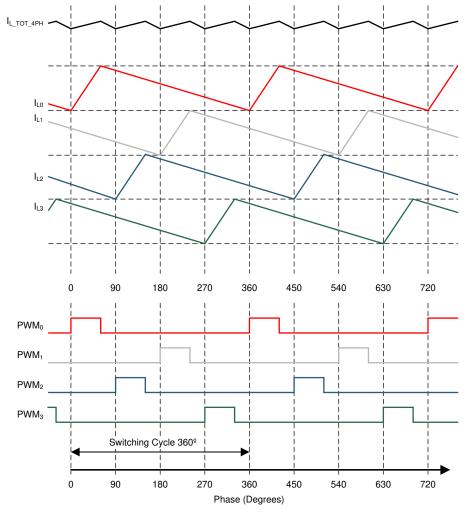
Interleaving switching action of the 4-phase converter is shown in  $\boxtimes$  7-2. The 4-phase converter switches each channel 90° apart. As a result, the 4-phase converter has an effective ripple frequency four times greater than the switching frequency of a one phase converter



Copyright © 2017, Texas Instruments Incorporated

图 7-1. Detailed Block Diagram Showing One Core





A. Graph is not in scale and is for illustrative purposes only.

图 7-2. Example of PWM Timings, Inductor Current Waveforms, and Total Output Current in 4-Phase Configuration.

#### 7.3.1.2 Multiphase Switcher Configurations

In single 4-phase output configuration the BUCK0 is master for the BUCK0, BUCK1, BUCK2, BUCK3 output.

In the multiphase configuration the control of the multiphase regulator settings is done using the control registers of the master buck. The following slave registers are ignored:

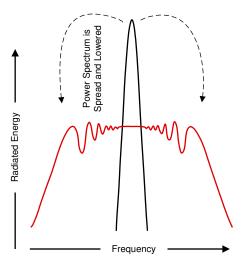
- · BUCKx CTRL1 register, except EN RDISx bit
- BUCKx DELAY register
- interrupt bits related to the slave buck, except BUCKx\_ILIM\_INT

#### 7.3.1.3 Buck Converter Load-Current Measurement

Buck load current can be monitored through I<sup>2</sup>C registers. The monitored buck converter is selected with the LOAD\_CURRENT\_BUCK\_SELECT[1:0] bits in SEL\_I\_LOAD register. A write to this selection register starts a current measurement sequence. The measurement sequence is 50 µs long, maximum. The LP875701-Q1 device can be configured to give out an interrupt (I\_LOAD\_READY bit in INT\_TOP1 register) after the load current measurement sequence is finished. Load current measurement interrupt can be masked with I\_LOAD\_READY\_MASK bit (TOP\_MASK1 register). The measurement result can be read from registers I\_LOAD\_1 and I\_LOAD\_2. Register I\_LOAD\_1 bits BUCK\_LOAD\_CURRENT[7:0] give out the LSB bits and register I\_LOAD\_2 bits BUCK\_LOAD\_CURRENT[9:8] the MSB bits. The measurement result BUCK\_LOAD\_CURRENT[9:0] LSB is 20 mA, and maximum value of the measurement corresponds to 20.46 A. If the selected buck regulator is a master phase, the measured current is the total value of the master and slave phases. If the selected buck regulator is a slave phase, the measured current is the output current of the selected phase.

#### 7.3.1.4 Spread-Spectrum Mode

Systems with periodic switching signals may generate a large amount of switching noise in a set of narrowband frequencies (the switching frequency and its harmonics). The usual solution to decrease noise coupling is to add EMI filters and shields to the boards. The LP875701-Q1 device has register selectable spread-spectrum mode which minimizes the need for output filters, ferrite beads, or chokes. In spread-spectrum mode, the switching frequency varies around the center frequency, reducing the EMI emissions radiated by the converter and associated passive components and PCB traces (see \$\mathbb{Z}\$ 7-3). This feature is available only when internal RC oscillator is used (PLL\_MODE[1:0] = 00 in PLL\_CTRL register), and it is enabled with the EN\_SPREAD\_SPEC bit (PIN FUNCTION register), and it affects all the buck cores.



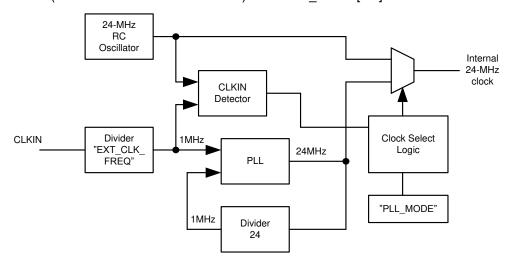
Where a fixed-frequency converter exhibits large amounts of spectral energy at the switching frequency, the spread-spectrum architecture of the LP875701-Q1 spreads that energy over a large bandwidth.

图 7-3. Spread-Spectrum Modulation

#### 7.3.2 Sync Clock Functionality

The LP875701-Q1 device contains a CLKIN input to synchronize switching clock of the buck regulator with the external clock. The block diagram of the clocking and PLL module is shown in 图 7-4. Depending on the PLL\_MODE[1:0] bits (in PLL\_CTRL register) and the external clock availability, the external clock is selected and interrupt is generated as shown in 表 7-2. The interrupt can be masked with SYNC\_CLK\_MASK bit in TOP\_MASK1 register. The nominal frequency of the external input clock is set by EXT\_CLK\_FREQ[4:0] bits (in PLL\_CTRL register) and it can be from 1 MHz to 24 MHz with 1-MHz steps. The external clock must be inside accuracy limits ( - 30%/+10%) for valid clock detection.

The NO\_SYNC\_CLK interrupt (in INT\_TOP1 register) is also generated in cases the external clock is expected but it is not available. These cases are start-up (read OTP-to-STANDBY transition) when PLL\_MODE[1:0] = 01 and regulator enable (STANDBY-to-ACTIVE transition) when PLL\_MODE[1:0] = 10.



Copyright © 2017, Texas Instruments Incorporated

图 7-4. Clock and PLL Module

# 表 7-2. PLL Operation

· · · · · · · · · · · · · · · · · · ·						
DEVICE OPERATION MODE	PLL_MODE[1:0]	PLL AND CLOCK DETECTOR STATE	INTERRUPT FOR EXTERNAL CLOCK	сьоск		
STANDBY	0h	Disabled	No	Internal RC		
ACTIVE	0h	Disabled	No	Internal RC		
STANDBY	1h	Enabled	When external clock appears or disappears	Automatic change to external clock when available		
ACTIVE	1h	Enabled	When external clock appears or disappears	Automatic change to external clock when available		
STANDBY	2h	Disabled	No	Internal RC		
ACTIVE	2h	Enabled	When external clock appears or disappears	Automatic change to external clock when available		
STANDBY	3h	Reserved				
ACTIVE	3h		Reserved			

#### 7.3.3 Power-Up

The power-up sequence for the LP875701-Q1 is as follows:

- VANA (and VIN\_Bx) reach minimum recommended level (V<sub>VANA</sub> > VANA<sub>UVLO</sub>).
- NRST is set to high level (or shorted to VANA). This initiates power-on-reset (POR), OTP reading and enables the system I/O interface. The I<sup>2</sup>C host must wait at least 1.2 ms before applying signals to ENx pins or writing or reading data to the LP875701-Q1.
- · Device goes to the STANDBY-mode .
- The host can change the default register setting by I<sup>2</sup>C if needed.
- The regulator(s) can be enabled/disabled by ENx pin(s) and by I<sup>2</sup>C interface.

#### 7.3.4 Regulator Control

#### 7.3.4.1 Enabling and Disabling Regulators

One or more regulators can be enabled when the device is in STANDBY or ACTIVE state. There are two ways for enable and disable the regulators:

- Using EN\_BUCK0 bit in BUCK0\_CTRL1 register (EN\_PIN\_CTRL0 register bit is 0h)
- Using EN1, EN2, EN3 control pins (EN\_BUCK0 bit is 1h AND EN\_PIN\_CTRL0 register bit is 1 in BUCK0\_CTRL1 register)

If the EN1, EN2, EN3 control pins are used for enable and disable then the control pin is selected with BUCK0\_EN\_PIN\_SELECT[1:0] bits (in BUCK0\_CTRL1 register). The delay from the control signal rising edge to enabling of the regulator is set by BUCK0\_STARTUP\_DELAY[3:0] bits and the delay from control signal falling edge to disabling of the regulator is set by BUCK0\_SHUTDOWN\_DELAY[3:0] bits in BUCK0\_DELAY register. The delays are valid only for EN1, EN2, EN3 signal control. The control with EN\_BUCK0 bit is immediate without the delays.

The control of the regulator (with 0-ms delays) is shown in  $\frac{1}{2}$  7-3.

1h

2h

#### 备注

The control of the regulator cannot be changed from one ENx pin to a different ENx pin because the control is ENx signal edge sensitive. The control from ENx pin to register bit and back to the original ENx pin can be done during operation.

CONTROL EN\_PIN\_CTRL BUCK0\_EN\_PI BUCKx OUTPUT VOLTAGE EN\_BUCK0 **EN1 PIN EN2 PIN EN3 PIN METHOD** N SELECTI1:01 Enable and disable Don't Care Don't Care Don't Care Don't Care Don't Care Disabled control with 1h 0h Don't Care Don't Care Don't Care Don't Care 1.0 Volt EN\_BUCK0 bit Disabled Enable and disable 1h 1h 0h Low Don't Care Don't Care control with EN1 1h 1h 0h Hiah Don't Care Don't Care 1.0 Volt Enable and disable 1h 1h 1h Don't Care Low Don't Care Disabled control with EN2 1h 1h 1h Don't Care Don't Care 1.0 Volt Enable and disable 1h 1h 2h Don't Care Don't Care Disabled Low

Don't Care

Don't Care

Hiah

表 7-3. Regulator Control

The regulator is enabled by the ENx pin or by I<sup>2</sup>C writing as shown in [8] 7-5. The soft-start circuit limits the inrush current during start-up. When the output voltage rises to 0.35-V level, the output voltage becomes slew-rate controlled. If there is a short circuit at the output and the output voltage does not increase above 0.35-V level in 1 ms, the regulator is disabled, and interrupt is set. When the output voltage reaches the Power-Good threshold level the BUCKx\_PG\_INT interrupt flag (in INT\_BUCK\_x register) is set. The Power-Good interrupt flag can be masked using BUCKx\_PG\_MASK bit (in BUCKx\_MASK register).

The ENx input pins have integrated pulldown resistors. The pulldown resistors are enabled by default, and the host can disable those with ENx PD bits (in CONFIG register).

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated

1.0 Volt

control with EN3

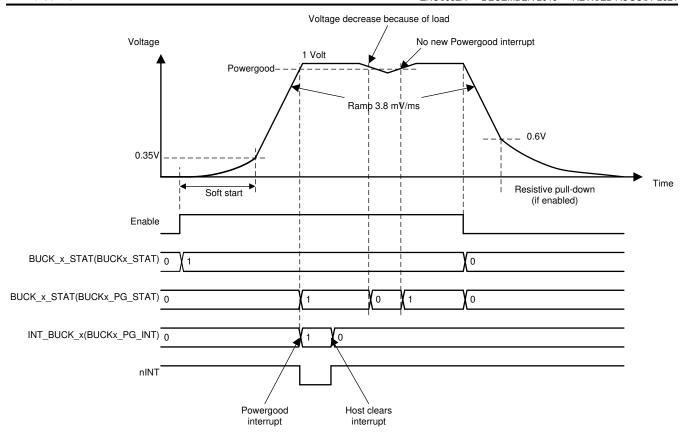


图 7-5. Regulator Enable and Disable

#### 7.3.5 Enable and Disable Sequences

The LP875701-Q1 device supports start-up and shutdown sequencing with programmable delay for the regulator output using one EN1, EN2, or EN3 control signal. The regulator is selected for delayed control with:

- EN\_BUCK0 = 1 (in BUCK0\_CTRL1 register)
- EN\_PIN\_CTRL0 = 1 (in BUCK0\_CTRL1 register)
- The ENABLE pin for control is selected with BUCK0\_EN\_PIN\_SELECT[1:0] (in BUCK0\_CTRL1 register)
- The delay from rising edge of ENx signal to the regulator enable is set by BUCK0\_STARTUP\_DELAY[3:0] bits (in BUCK0\_DELAY register) and
- The delay from falling edge of ENx signal to the regulator disable is set by BUCK0\_SHUTDOWN\_DELAY[3:0] bits (in BUCK0\_DELAY register)

There are four time steps available for start-up and shutdown sequences. The delay times are selected with DOUBLE\_DELAY bit in CONFIG register and HALF\_DELAY bit in PGOOD\_CTRL2 register as shown in 表 7-4.



表 7-4.	Start-Up	and	<b>Shutdown</b>	Delay	S
--------	----------	-----	-----------------	-------	---

0_STARTUP_DELAY or 0_SHUTDOWN_DELAY	DOUBLE_DELAY = 0h HALF_DELAY = 1h	DOUBLE_DELAY = 1h HALF_DELAY = 1h	DOUBLE_DELAY = 0h HALF_DELAY = 0h	DOUBLE_DELAY = 1h HALF_DELAY = 0h
0h	0 ms	0 ms	0 ms	0 ms
1h	0.32 ms	0.64 ms	1 ms	2 ms
2h	0.64 ms	1.28 ms	2 ms	4 ms
3h	0.96 ms	1.92 ms	3 ms	6 ms
4h	1.28 ms	2.56 ms	4 ms	8 ms
5h	1.6 ms	3.2 ms	5 ms	10 ms
6h	1.92 ms	3.84 ms	6 ms	12 ms
7h	2.24 ms	4.48 ms	7 ms	14 ms
8h	2.56 ms	5.12 ms	8 ms	16 ms
9h	2.88 ms	5.76 ms	9 ms	18 ms
Ah	3.2 ms	6.4 ms	10 ms	20 ms
Bh	3.52 ms	7.04 ms	11 ms	22 ms
Ch	3.84 ms	7.68 ms	12 ms	24 ms
dh	4.16 ms	8.32 ms	13 ms	26 ms
Eh	4.48 ms	8.96 ms	14 ms	28 ms
Fh	4.8 ms	9.6 ms	15 ms	30 ms

An example of start-up and shutdown sequences is shown in 🗵 7-6 and 🖺 7-7. The start-up and shutdown delays for the master buck regulator BUCK0 regulator is 1 ms and 4 ms . The delay settings are used only for enable/disable control with EN1, EN2, EN3 signals

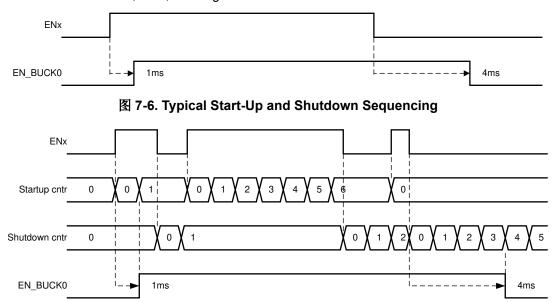


图 7-7. Start-Up and Shutdown Sequencing With Short ENx Low and High Periods

#### 7.3.6 Device Reset Scenarios

There are three reset methods implemented on the LP875701-Q1:

- Software reset with SW\_RESET register bit (in RESET register)
- · POR from rising edge of NRST signal
- Undervoltage lockout (UVLO) reset from VANA supply

A SW-reset occurs when SW\_RESET bit is written 1. The bit is automatically cleared after writing. This event disables all the regulators immediately, resets all the register bits to the default values and OTP bits are loaded (see 

7-11). I<sup>2</sup>C interface is not reset during software reset. The host must wait at least 1.2 ms after writing SW reset until making a new I<sup>2</sup>C read or write to the device.

If VANA supply voltage falls below UVLO threshold level or NRST signal is set low then all the regulators are disabled immediately, and all the register bits are reset to the default values. When the VANA supply voltage rises above UVLO threshold level AND NRST signal rises above threshold level an internal power-on reset (POR) occurs. OTP bits are loaded to the registers and a start-up is initiated according to the register settings. The host must wait at least 1.2 ms after POR until reading or writing to I<sup>2</sup>C interface.

## 7.3.7 Diagnosis and Protection Features

The LP875701-Q1 is capable of providing four levels of protection features:

- · Information of valid regulator output voltage which sets interrupt or PGOOD signal;
- · Warnings for diagnosis which sets interrupt;
- · Protection events which are disabling the regulators affected; and
- · Faults which are causing the device to shutdown.

The LP875701-Q1 sets the flag bits indicating what protection or warning conditions have occurred, and the nINT pin is pulled low. nINT is released again after a clear of flags is complete. The nINT signal stays low until all the pending interrupts are cleared.

When a fault is detected, it is indicated by a RESET\_REG interrupt flag (in INT2\_TOP register) after next start-up.

表 7-5. Summary of Interrupt Signals

EVENT	RESULT	INTERRUPT REGISTER AND BIT	INTERRUPT MASK	STATUS BIT	RECOVERY/INTERRUPT CLEAR
Current limit triggered (20-µs debounce)	Interrupt	INT_BUCKx = 1 BUCKx_ILIM_INT = 1	BUCKx_ILIM_MASK	BUCKx_ILIM_STAT	Write 1 to BUCKx_ILIM_INT bit Interrupt is not cleared if current limit is active
Short circuit (V <sub>VOUT</sub> < 0.35 V at 1 ms after enable) or overload (V <sub>VOUT</sub> decreasing below 0.35 V during operation, 1 ms debounce)	Regulator disable and interrupt	INT_BUCKx = 1 BUCKx_SC_INT = 1	N/A	N/A	Write 1 to BUCKx_SC_INT bit
Thermal warning	Interrupt	TDIE_WARN = 1	TDIE_WARN_MASK	TDIE_WARN_STAT	Write 1 to TDIE_WARN bit Interrupt is not cleared if temperature is above thermal warning level
Thermal shutdown	All regulators disabled and Output GPIOx set to low and interrupt	TDIE_SD = 1	N/A	TDIE_SD_STAT	Write 1 to TDIE_SD bit Interrupt is not cleared if temperature is above thermal shutdown level
VANA overvoltage (VANA <sub>OVP</sub> )	All regulators disabled and Output GPIOx set to low and interrupt	INT_OVP	N/A	OVP_STAT	Write 1 to INT_OVP bit Interrupt is not cleared if VANA voltage is above VANA OVP level
Power Good, output voltage reaches the programmed value	Interrupt	INT_BUCKx = 1 BUCKx_PG_INT = 1	BUCKx_PG_MASK	BUCKx_PG_STAT	Write 1 to BUCKx_PG_INT bit
GPIO	Interrupt	INT_GPIO	GPIO_MASK	GPIO_IN register	Write 1 to INT_GPIO bit
External clock appears or disappears	Interrupt	NO_SYNC_CLK <sup>(1)</sup>	SYNC_CLK_MASK	SYNC_CLK_STAT	Write 1 to NO_SYNC_CLK bit
Load current measurement ready	Interrupt	I_LOAD_READY = 1	I_LOAD_READY_MASK	N/A	Write 1 to I_LOAD_READY bit

## 表 7-5. Summary of Interrupt Signals (continued)

EVENT	RESULT	INTERRUPT REGISTER AND BIT	INTERRUPT MASK	STATUS BIT	RECOVERY/INTERRUPT CLEAR
Start-Up (NRST rising edge)	Device ready for operation, registers reset to default values and interrupt	RESET_REG = 1	RESET_REG_MASK	N/A	Write 1 to RESET_REG bit
Glitch on supply voltage and UVLO triggered (VANA falling and rising)	Immediate shutdown followed by power up, registers reset to default values and interrupt	RESET_REG = 1	RESET_REG_MASK	N/A	Write 1 to RESET_REG bit
Software requested reset	Immediate shutdown followed by power up, registers reset to default values and interrupt	RESET_REG = 1	RESET_REG_MASK	N/A	Write 1 to RESET_REG bit

(1) Interrupt is generated during clock detector operation and in case clock is not available when clock detector is enabled.

#### 7.3.7.1 Power-Good Information (PGOOD pin)

In addition to the interrupt based indication of current limit and Power-Good level the LP875701-Q1 device supports the indication with PGOOD signal. Either voltage and current monitoring or a voltage monitoring only can be selected for PGOOD indication. This selection is individual for all buck regulators (select master phase for multiphase regulator) and is set by PGx\_SEL[1:0] bits (in PGOOD\_CTRL1 register). When both voltage and current are monitored, PGOOD signal active indicates that regulator output is inside the Power-Good voltage window and that load current is below I<sub>LIM FWD</sub>. If only voltage is monitored, then the current monitoring is ignored for the PGOOD signal. When a regulator is disabled, the monitoring is automatically masked to prevent it forcing PGOOD inactive. This allows connecting PGOOD signals from various devices together when open-drain outputs are used. When regulator voltage is transitioning from one target voltage to another, the voltage monitoring PGOOD signal is set inactive. The monitoring from all the output rails are combined, and PGOOD is active only if all the sources shows active status. The status from all the voltage rails are summarized in ₹ 7-6.

If the PGOOD signal is inactive or it changes the state to inactive, the source for the state can be read from PGOOD\_FLT register. During reading all the PGx\_FLT bit are cleared that are not driving the PGOOD inactive. When PGOOD signal goes active, the host must read the PGOOD\_FLT register to clear all the bits. The PGOOD signal follows the status of all the monitored outputs.

The PGOOD signal can be also configured so that it stays in the inactive state even when the monitored outputs are valid but there are PGx\_FLT bits pending clearance in PGOOD\_FLT register. This mode of operation is selected by setting EN PGFLT STAT bit to 1 (in PGOOD CTRL2 register).

The type of output voltage monitoring for PGOOD signal is selected by PGOOD\_WINDOW bit (in PGOOD\_CTRL2 register). If the bit is 0, only undervoltage is monitored; if the bit is 1, both undervoltage and overvoltage are monitored.

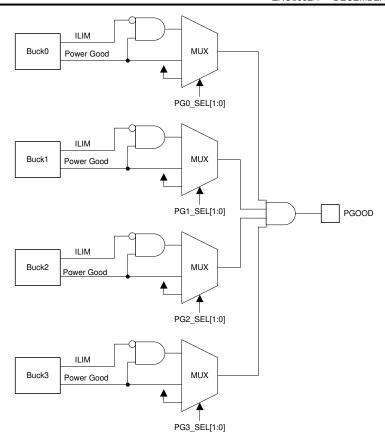
The polarity and the output type (push-pull or open-drain) are selected by PGOOD\_POL and PGOOD\_OD bits in PGOOD\_CTRL2 register.

The filtering time for invalid output voltage is always typically 7 µs and for valid output voltage the filtering time is selected with PGOOD\_SET\_DELAY bit (in PGOOD\_CTRL2 register). The Power-Good waveforms are shown in ₹ 7-9.

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated





Copyright © 2017, Texas Instruments Incorporated

# 图 7-8. PGOOD Block Diagram

## 表 7-6. PGOOD Operation

STATUS / USE CASE	CONDITION	INPUT TO PGOOD SIGNAL
Buck not selected for PGOOD monitoring	PGx_SEL = 00 (in PGOOD_CTRL1 register)	Active
Buck disabled		Active



#### 表 7-6. PGOOD Operation (continued)

STATUS / USE CASE	CONDITION	INPUT TO PGOOD SIGNAL
BUCK SELECTED FOR PGOOD MONITO	RING	
Buck start-up delay		Inactive
Buck soft start	V <sub>OUT</sub> < 0.35 V	Inactive
Buck voltage ramp-up	0.35 V < V <sub>OUT</sub> < V <sub>SET</sub>	Inactive
Output voltage within window limits after start-up	Must be inside limits longer than debounce time	Active
Output voltage inside voltage window and current limit active	Current limit active longer than debounce time	Active (if only voltage monitoring selected) Inactive (if also current monitoring selected)
Output voltage spikes (overvoltage or undervoltage)	If spikes are outside voltage window longer than debounce time	Inactive
Voltage setting change, output voltage ramp		Inactive
Output voltage within window limits after voltage change	Must be inside limits longer than debounce time	Active
Buck shutdown delay		Active
Buck output voltage ramp down		Active
Buck disabled by thermal shutdown and interrupt pending		Inactive
Buck disabled by overvoltage and interrupt pending		Inactive
Buck disabled by short-circuit detection and interrupt pending		Inactive

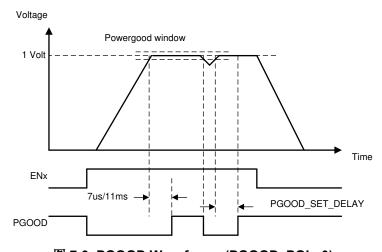


图 7-9. PGOOD Waveforms (PGOOD\_POL=0)

#### 7.3.7.2 Warnings for Diagnosis (Interrupt)

#### 7.3.7.2.1 Output Power Limit

The regulators have output peak current limits. The peak current limits are described in Electrical Characteristic Table. If the load current is increased so that the current limit is triggered, the regulator continues to regulate to the limit current level (current peak regulation, peak on each switching cycle). The voltage may decrease if the load current is higher than the average output current. If the current regulation continues for 20 µs, the LP875701-Q1 device sets the BUCKx\_ILIM\_INT bit (in INT\_BUCKx register) and pulls the nINT pin low. The host processor can read BUCKx\_ILIM\_STAT bits (in BUCKx\_STAT register) to see if the regulator is still in peak current regulation mode.

If the load is so high that the output voltage decreases below a 350-mV level, the LP875701-Q1 device disables the regulator and sets the BUCKx\_SC\_INT bit (in INT\_BUCKx register). In addition the BUCKx\_STAT bit (in

BUCKx\_STAT register) is set to 0. The interrupt is cleared when the host processor writes 1 to BUCKx\_SC\_INT bit. The overload situation is shown in § 7-10.

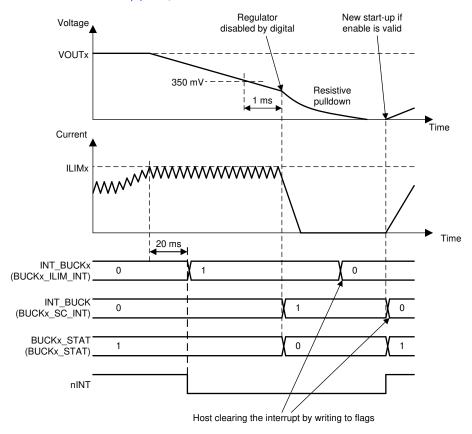


图 7-10. Overload Situation

#### 7.3.7.2.2 Thermal Warning

The LP875701-Q1 device includes a monitoring feature against overtemperature by setting an interrupt for host processor. The threshold level of the thermal warning is selected with TDIE\_WARN\_LEVEL bit (in CONFIG register).

If the LP875701-Q1 device temperature increases above thermal warning level the device sets TDIE\_WARN bit (in INT\_TOP1 register) and pulls nINT pin low. The status of the thermal warning can be read from TDIE\_WARN\_STAT bit (in TOP\_STAT register), and the interrupt is cleared by writing 1 to TDIE\_WARN bit.

#### 7.3.7.3 Protection (Regulator Disable)

If the regulator is disabled because of protection or fault (short-circuit protection, overload protection, thermal shutdown, overvoltage protection, or UVLO), the output power FETs are set to high-impedance mode, and the output pulldown resistor is enabled (if enabled with EN\_RDISx bits in BUCKx\_CTRL1 register). The turnoff time of the output voltage is defined by the output capacitance, load current, and the resistance of the integrated pulldown resistor. The pulldown resistors are active as long as VANA voltage is above approximately a 1.2-V level.

#### 7.3.7.3.1 Short-Circuit and Overload Protection

A short-circuit protection feature lets the LP875701-Q1 device protect itself and external components against short circuit at the output or against overload during start-up. The fault threshold is 350 mV, the protection is triggered, and the regulator is disabled if the output voltage is below the threshold level 1 ms after the regulator is enabled.

In a similar way the overload situation is protected during normal operation. If the voltage on the feedback pin of the regulator falls to less than 0.35 V and stays lower the threshold level for 1 ms, the regulator is disabled.

In the short-circuit and overload situations the BUCKx\_SC\_INT (in INT\_BUCKx register) and the INT\_BUCKx bits (in INT\_TOP1 register) are set to 1, the BUCKx\_STAT bit (in BUCKx\_STAT register) is set to 0, and the nINT signal is pulled low. The host processor clears the interrupt by writing 1 to the BUCKx\_SC\_INT bit. After clearing the interrupt the regulator makes a new start-up attempt if the regulator is in enabled state.

#### 7.3.7.3.2 Overvoltage Protection

The LP875701-Q1 device monitors the input voltage from the VANA pin in standby and active operation modes. If the input voltage rises above VANA<sub>OVP</sub> voltage level, all the regulators are disabled, pulldown resistors discharge the output voltages (if EN\_RDISx = 1 in BUCKx\_CTRL1 register), GPIOs that are configured to outputs are set to logic low level, nINT signal is pulled low, INT\_OVP bit (in INT\_TOP1 register) is set to 1, and BUCKx\_STAT bits (in BUCK\_x\_STAT register) are set to 0. The host processor clears the interrupt by writing 1 to the INT\_OVP bit. If the input voltage is above the overvoltage detection level the interrupt is not cleared. The host can read the status of the overvoltage from the OVP\_STAT bit (in TOP\_STAT register). Regulators cannot be enabled as long as the input voltage is above overvoltage detection level or the overvoltage interrupt is pending.

#### 7.3.7.3.3 Thermal Shutdown

The LP875701-Q1 has an overtemperature protection function that operates to protect the device from short-term misuse and overload conditions. When the junction temperature exceeds around 150°C, the regulators are disabled, the TDIE\_SD bit (in INT\_TOP1 register) is set to 1, the nINT signal is pulled low, and the device goes to the STANDBY state. The nINT pin is cleared by writing 1h to the TDIE\_SD bit. If the temperature is above thermal shutdown level the interrupt is not cleared. The host can read the status of the thermal shutdown from the TDIE\_SD\_STAT bit (in TOP\_STAT register). Regulators cannot be enabled as long as the junction temperature is above thermal shutdown level or the thermal shutdown interrupt is pending.

#### 7.3.7.4 Fault (Power Down)

#### 7.3.7.4.1 Undervoltage Lockout

When the input voltage falls below VANA<sub>UVLO</sub> at the VANA pin, the buck converters are disabled immediately, and the output capacitors are discharged using the pulldown resistor, and the LP875701-Q1 device goes to the SHUTDOWN state. When the VANA voltage is greater than the UVLO threshold level and NRST signal is high, the device powers up to STANDBY state.

If the reset interrupt is unmasked by default (RESET\_REG\_MASK = 0 in TOP\_MASK2 register) the RESET\_REG interrupt (in INT\_TOP2 register) indicates that the device has been in SHUTDOWN. The host processor must clear the interrupt by writing 1 to the RESET\_REG bit. If the host processor reads the RESET\_REG flag after detecting an nINT low signal, it knows that the input supply voltage has been below UVLO level (or the host has requested reset), and the registers are reset to default values.

## 7.3.8 GPIO Signal Operation

The LP875701-Q1 device supports up to 3 GPIO signals. The GPIO signals are multiplexed with enable signals. The selection between enable and GPIO function is set with GPIOx\_SEL bits in PIN\_FUNCTION register. The GPIOs are mapped to EN signals so that:

- EN1 is multiplexed with GPIO1
- EN2 is multiplexed with GPIO2
- EN3 is multiplexed with GPIO3

When the pin is selected for GPIO function, additional bits defines how the GPIO operates:

- GPIOx DIR defines the direction of the GPIO, input or output (GPIO CONFIG register)
- GPIOx\_OD defines the type of the output when the GPIO is set to output, either push-pull with VANA level or open-drain (GPIO\_CONFIG register)

When the GPIOx is defined as output, the logic level of the pin is set by GPIOx\_OUT bit (in GPIO\_OUT register).

When the GPIOx is defined as input, the logic level of the pin can be read from GPIOx\_IN bit (in GPIO\_IN register).

The control of the GPIOs configured to outputs can be included to start-up and shutdown sequences. The GPIO control for a sequence with ENx signal is selected by EN\_PIN\_CTRL\_GPIOx and EN\_PIN\_SELECT\_GPIOx bits (in PIN\_FUNCTION register). The delays during start-up and shutdown are set by GPIOx\_STARTUP\_DELAY[3:0] and GPIOx\_SHUTDOWN\_DELAY[3:0] bits (in GPIOx\_DELAY register) in the same way as control of the regulators.

The GPIOx signals have a selectable pulldown resistor. The pulldown resistors are selected by ENx\_PD bits (in CONFIG register).

#### 备注

The control of the GPIOx pin cannot be changed from one ENx pin to a different ENx pin because the control is ENx signal edge sensitive. The control from ENx pin to register bit and back to the original ENx pin can be done during operation.

#### 7.3.9 Digital Signal Filtering

The digital signals have a debounce filtering. The signal/supply is sampled with a clock signal and a counter. This results as an accuracy of one clock period for the debounce window.

Copyright © 2022 Texas Instruments Incorporated



表 7-7. Digital Signal Filtering

ye i i i signai i itomig					
EVENT	SIGNAL/SUPPLY	RISING EDGE DEBOUNCE TIME	FALLING EDGE DEBOUNCE TIME		
Enable and disable for BUCKx	EN1	3 µs <sup>(1)</sup>	3 µs <sup>(1)</sup>		
Enable and disable for BUCKx	EN2	3 µs <sup>(1)</sup>	3 µs <sup>(1)</sup>		
Enable and disable for BUCKx	EN3	3 μs <sup>(1)</sup>	3 µs <sup>(1)</sup>		
VANA UVLO	VANA	20 μs (VANA voltage rising)	Immediate (VANA voltage falling)		
VANA overvoltage	VANA	20 μs (VANA voltage rising)	20 μs (VANA voltage falling)		
Thermal warning	TDIE_WARN	20 μs	20 μs		
Thermal shutdown	TDIE_SD	20 μs	20 μs		
Current limit	VOUTx_ILIM	20 μs	20 μs		
Overload	FB_B0, FB_B1, FB_B2, FB_F3	1 ms	20 μs		
Power-good interrupt	FB_B0, FB_B1, FB_B2, FB_F3	20 μs	20 μs		
PGOOD pin (voltage monitoring)	PGOOD / FB_B0, FB_B1, FB_B2, FB_F3	4-8 μs (start-up debounce time during start-up)	4 to 8 μs		
PGOOD pin (current monitoring)	PGOOD	20 μs	20 μs		

<sup>(1)</sup> No glitch filtering, only synchronization.

#### 7.4 Device Functional Modes

#### 7.4.1 Modes of Operation

**SHUTDOWN:** The NRST voltage is below threshold level. All switch, reference, control, and bias circuitry of the LP875701-Q1 device are turned off.

**READ OTP:** The primary supply voltage VANA is above VANA<sub>UVLO</sub> level and NRST voltage is above threshold level. The regulators are disabled and the reference and bias circuitry of the

LP875701-Q1 are enabled. The OTP bits are loaded to registers.

**STANDBY:** The primary supply voltage VANA is above VANA<sub>UVLO</sub> level and NRST voltage is above

threshold level. The regulators are disabled and the reference, control and bias circuitry of the LP875701-Q1 are enabled. All registers can be read or written by the host processor via the

system serial interface. The regulators can be enabled if needed.

**ACTIVE:** The primary supply voltage VANA is above VANA<sub>UVLO</sub> level and NRST voltage is above

threshold level. At least one regulated DC/DC converter is enabled. All registers can be read or

written by the host processor via the system serial interface.

The operating modes and transitions between the modes are shown in 图 7-11.

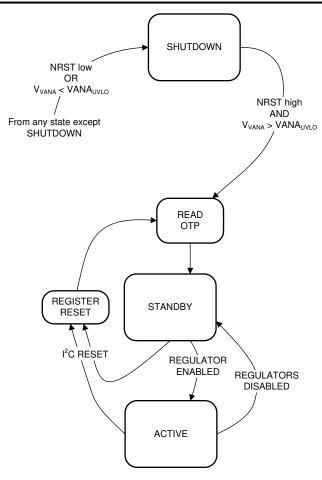


图 7-11. Device Operation Modes

# 7.5 Programming

## 7.5.1 I<sup>2</sup>C-Compatible Interface

The I<sup>2</sup>C-compatible synchronous serial interface provides access to the programmable functions and registers on the device. This protocol uses a two-wire interface for bidirectional communications between the devices connected to the bus. The two interface lines are the serial data line (SDA), and the serial clock line (SCL). Each device on the bus is assigned a unique address and acts as either a master or a slave depending on whether it generates or receives the serial clock SCL. The SCL and SDA lines must each have a pullup resistor placed somewhere on the line and stays HIGH even when the bus is idle. Note: CLK pin is not used for serial bus data transfer. The LP875701-Q1 supports standard mode (100 kHz), fast mode (400 kHz), fast mode+ (1 MHz), and high-speed mode (3.4 MHz).

#### 7.5.1.1 Data Validity

The data on the SDA line must be stable during the HIGH period of the clock signal (SCL). In other words, the state of the data line can only be changed when clock signal is LOW.



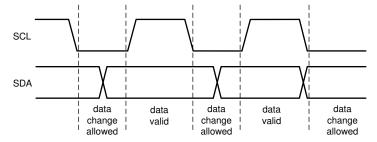


图 7-12. Data Validity Diagram

## 7.5.1.2 Start and Stop Conditions

The LP875701-Q1 is controlled through the an  $I^2C$ -compatible interface. START and STOP conditions classify the beginning and end of the  $I^2C$  session. A START condition is defined as SDA transitions from HIGH to LOW while SCL is HIGH. A STOP condition is defined as SDA transition from LOW to HIGH while SCL is HIGH. The  $I^2C$  master always generates the START and STOP conditions.

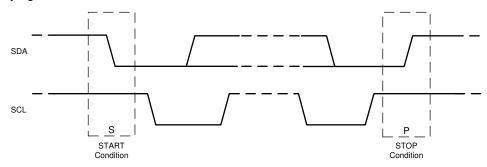


图 7-13. Start and Stop Sequences

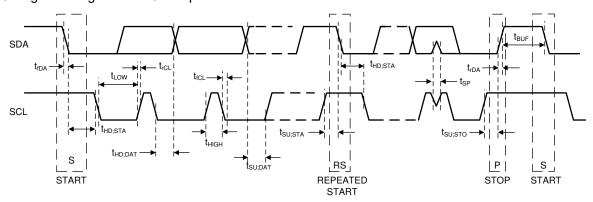


图 7-14. I<sup>2</sup>C-Compatible Timing

#### 7.5.1.3 Transferring Data

Each byte put on the SDA line must be eight bits long, with the most significant bit (MSB) being transferred first. Each byte of data has to be followed by an acknowledge bit. The acknowledge related clock pulse is generated by the master. The master releases the SDA line (HIGH) during the acknowledge clock pulse. The LP875701-Q1 pulls down the SDA line during the 9th clock pulse, signifying an acknowledge. The LP875701-Q1 generates an acknowledge after each byte has been received.

There is one exception to the *acknowledge after each byte* rule. When the master is the receiver, it must indicate to the transmitter an end of data by not-acknowledging (*negative acknowledge*) the last byte clocked out of the slave. This *negative acknowledge* still includes the acknowledge clock pulse (generated by the master), but the SDA line is not pulled down.

#### 备注

If the NRST signal is low during I<sup>2</sup>C communication the LP875701-Q1 device does not drive SDA line. The ACK signal and data transfer to the master is disabled at that time.

After the START condition, the bus master sends a chip address. This address is seven bits long followed by an eighth bit which is a data direction bit (READ or WRITE). For the eighth bit, a 0 indicates a WRITE and a 1 indicates a READ. The second byte selects the register to which the data will be written. The third byte contains data to write to the selected register.

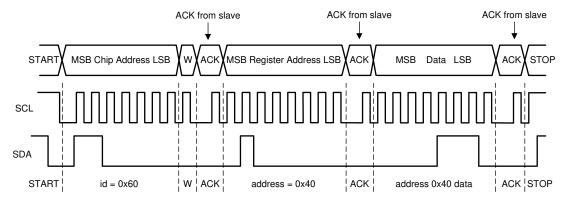
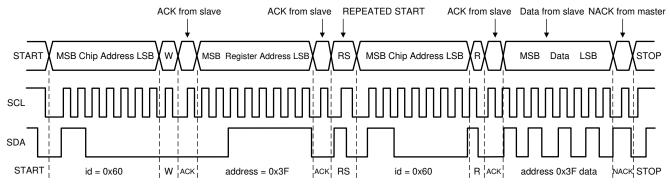


图 7-15. Write Cycle (w = write; SDA = 0), id = Device Address = 0x60 for LP875701-Q1



When READ function is to be accomplished, a WRITE function must precede the READ function as shown above.

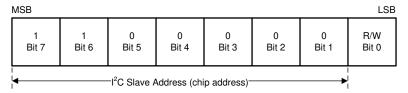
图 7-16. Read Cycle (r = read; SDA = 1), id = Device Address = 0x60 for LP875701-Q1

#### 7.5.1.4 I<sup>2</sup>C-Compatible Chip Address

#### 备注

The device address for the LP875701-Q1 is defined in the Technical Reference Manual (TRM).

After the START condition, the  $I^2C$  master sends the 7-bit address followed by an eighth bit, read or write (R/W). R/W = 0 indicates a WRITE and R/W = 1 indicates a READ. The second byte following the device address selects the register address to which the data will be written. The third byte contains the data for the selected register.



A. Here device address is 1100000Bin = 60Hex.

图 7-17. Example Device Address

#### 7.5.1.5 Auto-Increment Feature

The auto-increment feature allows writing several consecutive registers within one transmission. Each time an 8-bit word is sent to the device, the internal address index counter is incremented by one and the next register is written. 表 7-8 below shows writing sequence to two consecutive registers. Note that auto increment feature does not work for read.

表 7-8. Auto-Increment Example

MASTER ACTION	START	DEVICE ADDRESS = 0x60	WRITE		REGISTER ADDRESS		DATA		DATA		STOP
LP875701-Q1				ACK		ACK		ACK		ACK	

#### 7.6 Register Maps

#### 7.6.1 Register Descriptions

The LP875701-Q1 is controlled by a set of registers through the  $I^2C$ -compatible interface. The device registers, their addresses, and their abbreviations are listed in  $\frac{1}{8}$  7-9. A more detailed description is given in  $\frac{1}{7}$  7.6.1.2 through  $\frac{1}{7}$  7.6.1.30.

#### 备注

This register map describes the default values for bits which are not read from OTP memory. The orderable code and the default register bit values are defined in part number specific Technical Reference Manual.

Submit Document Feedback



# 表 7-9. Summary of LP875701-Q1 Control Registers

Address	Register	Access	D7	D6	D5	D4	D3	D2	D1	D0	
0x00	DEV_REV	R	DEVICE	 E_ID[1:0]	ALL_LAYER[1:0]		METAL_LAYER[3:0]				
0x01	OTP_REV	R			1	OTP_	_ID[7:0]				
0x02	BUCK0_CTRL1	R/W	EN_BUCK0	EN_PIN_CTRL0	BUCK0_EN_PI	NSELECT[1:0]	Reserved - do not use	EN_RDIS0	Reserved - Do not use	Reserved - Do not use	
0x03	Reserved - Do not use	RW		Reserved - Do not use							
0x04	Reserved - Do not use	RW		Reserved - Do not use							
0x05	Reserved - Do not use	RW				Reserved	- Do not use				
0x06	Reserved - Do not use	RW				Reserved	- Do not use				
0x07	Reserved - Do not use	RW				Reserved	- Do not use				
0x08	Reserved - Do not use	RW				Reserved	- Do not use				
0x09	Reserved - Do not use	RW				Reserved	- Do not use				
0x0A	Reserved - Do not use	RW				Reserved	- Do not use				
0x0B	Reserved - Do not use	RW				Reserved	- Do not use				
0x0C	Reserved - Do not use	RW				Reserved	- Do not use				
0x0D	Reserved - Do not use	RW				Reserved	- Do not use				
0x0E	Reserved - Do not use	RW				Reserved	- Do not use				
0x0F	Reserved - Do not use	RW				Reserved	- Do not use				



# 表 7-9. Summary of LP875701-Q1 Control Registers (continued)

Address	Register	Access	D7	D6	D5	D4	D3	D2	D1	D0	
0x10	Reserved - Do not use	RW		Reserved - Do not use							
0x11	Reserved - Do not use	RW		Reserved - Do not use							
0x12	BUCK0_DELAY	R/W		BUCK0_SHUTDOWN_DELAY[3:0] BUCK0_STARTUP_DELAY[3:0]							
0x13	Reserved - Do not use	RW		Reserved - Do not use							
0x14	Reserved - Do not use	RW		Reserved - Do not use							
0x15	Reserved - Do not use	RW		Reserved - Do not use							
0x16	GPIO2_DELAY	R/W		GPI02_SHUTDOWN_DELAY[3:0] GPI02_STARTUP_DELAY[3:0]					UP_DELAY[3:0]		
0x17	GPIO3_DELAY	R/W		GPIO3_SHUTDOWN_DELAY[3:0] GPIO3_STARTUP_DELAY[3:0]							
0x18	RESET	R/W		Reserved					SW_RESET		
0x19	CONFIG	R/W	DOUBLE_DELAY	CLKIN_PD	Reserved	EN3_PD	TDIE_WARN_LE VEL	EN2_PD	EN1_PD	Reserved	
0x1A	INT_TOP1	R/W	Reserved	INT_BUCK23	INT_BUCK01	NO_SYNC_CLK	TDIE_SD	TDIE_WARN	INT_OVP	I_LOAD_READY	
0x1B	INT_TOP2	R/W	Reserved						RESET_REG		
0x1C	INT_BUCK_0_1	R/W	Reserved	BUCK1_PG_INT	BUCK1_SC_INT	BUCK1_ILIM_INT	Reserved	BUCK0_PG_INT	BUCK0_SC_INT	BUCK0_ILIM_INT	
0x1D	INT_BUCK_2_3	R/W	Reserved	BUCK3_PG_INT	BUCK3_SC_INT	BUCK3_ILIM_INT	Reserved	BUCK2_PG_INT	BUCK2_SC_INT	BUCK2_ILIM_INT	
0x1E	TOP_STAT	R	Reserved SYNC_CLK_STA T				TDIE_SD_STAT	TDIE_WARN_ST AT	OVP_STAT	Reserved	
0x1F	BUCK_0_1_STAT	R	BUCK1_STAT	BUCK1_PG_STA T	Reserved	BUCK1_ILIM_ST AT	BUCK0_STAT	BUCK0_PG_STA T	Reserved	BUCK0_ILIM_ST AT	
0x20	BUCK_2_3_STAT	R	BUCK3_STAT	BUCK3_PG_STA T	Reserved	BUCK3_ILIM_ST AT	BUCK2_STAT	BUCK2_PG_STA T	Reserved	BUCK2_ILIM_ST AT	
0x21	TOP_MASK1	R/W	Reserved Reserved			SYNC_CLK_MAS K	Reserved	TDIE_WARN_MA	Reserved	I_LOAD_READY_ MASK	
0x22	TOP_MASK2	R/W		,		Reserved				RESET_REG_MA	

## 表 7-9. Summary of LP875701-Q1 Control Registers (continued)

Address	Register	Access	D7	D6	D5	D4	D3	D2	D1	D0	
0x23	BUCK_0_1_MAS K	R/W	Reserved	BUCK1_PG_MAS K	Reserved	BUCK1_ILIM_MA SK	Reserved	BUCK0_PG_MAS K	Reserved	BUCK0_ILIM_MA SK	
0x24	BUCK_2_3_MAS K	R/W	Reserved	BUCK3_PG_MAS K	Reserved	BUCK3_ILIM_MA SK	Reserved	BUCK2_PG_MAS K	Reserved	BUCK2_ILIM_MA SK	
0x25	SEL_I_LOAD	R/W		Reserved					LOAD_CURRENT_BUCK_SELECT[1 :0]		
0x26	I_LOAD_2	R			Rese	erved			BUCK_LOAD_	CURRENT[9:8]	
0x27	I_LOAD_1	R		BUCK_LOAD_CURRENT[7:0]							
0x28	PGOOD_CTRL1	R/W	PG3_S	SEL[1:0]	PG2_SEL[1:0] PG1_S			EL[1:0]	PG0_S	EL[1:0]	
0x29	PGOOD_CTRL2	R/W	HALF_DELAY	EN_PG0_NINT	PGOOD_SET_DE LAY	EN_PGFLT_STAT	Reserved	PGOOD_WINDO W	PGOOD_OD	PGOOD_POL	
0x2A	PGOOD_FLT	R					PG3_FLT	PG2_FLT	PG1_FLT	PG0_FLT	
0x2B	PLL_CTRL	R/W	PLL_MC	DDE[1:0]	Reserved	EXT_CLK_FREQ[4:			)]	1	
0x2C	PIN_FUNCTION	R/W	EN_SPREAD_SP EC	EN_PIN_CTRL_G PIO3	EN_PIN_SELECT _GPIO3	EN_PIN_CTRL_G PIO2	EN_PIN_SELECT _GPIO2	GPIO3_SEL	GPIO2_SEL	GPIO1_SEL	
0x2D	GPIO_CONFIG	R/W	Reserved	GPIO3_OD	GPIO2_OD	GPIO1_OD	Reserved	GPIO3_DIR	GPIO2_DIR	GPIO1_DIR	
0x2E	GPIO_IN	R	Reserved GPIO3_IN C					GPIO2_IN	GPIO1_IN		
0x2F	GPIO_OUT	R/W		Reserved GPI03_OUT GPI02_OUT GPI01_O						GPIO1_OUT	



Complex bit access types are encoded to fit into small table cells. 表 7-10 shows the codes that are used for access types in this section.

### 表 7-10. Access Type Codes

₹ 1-10. Access Type Codes					
Access Type	Code	Description			
Read Type					
R	R	Read			
RC	R	Read			
R-0	R	Read			
Write Type					
W	W	Write			
W1C	W	Write			
	1C	1 to clear			
Reset or Default Value					
-n		Value after reset or the default value			
X		Value is set by OTP memory			



## 7.6.1.1 DEV\_REV

Address: 0x00

D7	D6	D5	D4	D3	D2	D1	D0
DEVIC	= ID[1:0]	ALL LAYER[1:0]			METAL I	AYFR[3:0]	

Bits	Field	Type	Default	Description
7:6	DEVICE_ID[1:0]	R	Х	Device specific ID code.
5:4	ALL_LAYER[1:0]	R	1h	Shows the all layer version of the device:  0h = First all layer version (ES1.0 silicon)  1h = Second all layer version (ES2.x silicon)  2h = Third all layer version  3h = Fourth all layer version
3:0	METAL_LAYER [3:0]	R	2h	Shows the metal layer version of the device:  0h = All layer version  1h = First metal layer spin  Fh = 15th metal layer spin

## 7.6.1.2 OTP\_REV

Address: 0x01

D7	D6	D5	D4	D3	D2	D1	D0		
	OTP ID(7:01								

Bits	Field	Type	Default	Description
7:0	OTP_ID[7:0]	R	Х	Identification code of the OTP EPROM version

## 7.6.1.3 BUCK0\_CTRL1

Address: 0x02

D7	D6	D5	D4	D3	D2	D1	D0
EN_BUCK0	EN_PIN_CTRL	BUCK0_EN_PI	N_SELECT[1:0]	Reserved	EN_RDIS0	Reserved	Reserved

Bits	Field	Type	Default	Description
7	EN_BUCK0	R/W	Х	This bit enables the BUCK0 regulator  0h = BUCK0 regulator is disabled  1h = BUCK0 regulator is enabled
6	EN_PIN_CTRL0	R/W	Х	This bit enables the EN1, EN2, EN3 pin control for the BUCK0 regulator  0h = Only the EN_BUCK0 bit controls the BUCK0 regulator  1h = EN_BUCK0 bit AND ENx pin control the BUCK0 regulator
5:4	BUCK0_EN_PIN_S ELECT[1:0]	R/W	Х	This bit enables the EN1, EN2, EN3 pin control for the BUCK0 regulator  0h = EN_BUCK0 bit AND EN1 pin control BUCK0  1h = EN_BUCK0 bit AND EN2 pin control BUCK0  2h = EN_BUCK0 bit AND EN3 pin control BUCK0  3h = Reserved
3	Reserved	R/W	0h	Reserved, do not use
2	EN_RDIS0	R/W	1h	This bit enables the output of the discharge resistor when the BUCK0 regulator is disabled 0h = Discharge resistor disabled 1h = Discharge resistor enabled
1	Reserved	R/W	Х	Reserved, do not use
0	Reserved	R/W	Х	Reserved, do not use



## 7.6.1.4 BUCK0\_DELAY

Address: 0x12

D7	D6	D5	D4	D3	D2	D1	D0

BUCKO SHUTDOWN DELAY[3:0]	BUCKO STARTUP DELAY[3:0]

Bits	Field	Type	Default	Description
7:4	BUCK0_SHUTDOW N_DELAY[3:0]	R/W	Х	Shutdown delay of the BUCK0 regulator from the falling edge of the ENx signal (the DOUBLE_DELAY bit is set to 0h in the CONFIG register and the HALF_DELAY bit is set to 0h in the PGOOD_CTRL2 register). For other delay options, see the <i>Start-Up and Shutdown Delays</i> table.  0h = 0 ms 1h = 1 ms Fh = 15 ms
3:0	BUCK0_STARTUP_ DELAY[3:0]	R/W	Х	Start-Up delay the of the BUCK0 regulator from the rising edge of the ENx signal (the DOUBLE_DELAY bit is set to 0h in the CONFIG register and the HALF_DELAY bit is set to 0h in the PGOOD_CTRL2 register). For other delay options, see the <i>Start-Up and Shutdown Delays</i> table.  0h = 0 ms 1h = 1 ms Fh = 15 ms

## 7.6.1.5 GPIO2\_DELAY

Address: 0x16

D7 D6 D5 D4 D3 D2 D1 D0

GPIO2 SHUTDOWN DELAY[3:0]	GPIO2 STARTUP DELAY[3:0]

Bits	Field	Type	Default	Description
7:4	GPIO2_SHUTDOW N_DELAY[3:0]	R/W	Х	Delay for the GPIO2 falling edge from the falling edge of the ENx signal (the DOUBLE_DELAY bit is set to 0h in the CONFIG register and the HALF_DELAY bit is set to 0h in the PGOOD_CTRL2 register). For other delay options, see the <i>Start-Up and Shutdown Delays</i> table.  0h = 0 ms 1h = 1 ms Fh = 15 ms
3:0	GPIO2_STARTUP_ DELAY[3:0]	R/W	Х	Delay for the GPIO2 rising edge from the rising edge of the ENx signal (the DOUBLE_DELAY bit is set to 0h in the CONFIG register and the HALF_DELAY bit is set to 0h in the PGOOD_CTRL2 register). For other delay options, see the <i>Start-Up and Shutdown Delays</i> table.  0h = 0 ms 1h = 1 ms Fh = 15 ms

Submit Document Feedback



## 7.6.1.6 GPIO3\_DELAY

Address: 0x17

D7	D6	D5	D4	D3	D2	D1	D0

GPIO3 SHUTDOWN DELAY[3:0]	GPIO3 STARTUP DELAY[3:0]

Bits	Field	Type	Default	Description
7:4	GPIO3_SHUTDOW N_DELAY[3:0]	R/W	Х	Delay for the GPIO3 falling edge from the falling edge of the ENx signal (the DOUBLE_DELAY bit is set to 0h in the CONFIG register and the HALF_DELAY bit is set to 0h in the PGOOD_CTRL2 register). For other delay options, see the <i>Start-Up and Shutdown Delays</i> table.  0h = 0 ms 1h = 1 ms Fh = 15 ms
3:0	GPIO3_STARTUP_ DELAY[3:0]	R/W	Х	Delay for GPIO3 rising edge from rising edge of ENx signal (the DOUBLE_DELAY bit is set to 0h in the CONFIG register and the HALF_DELAY bit is set to 0h in the PGOOD_CTRL2 register). For other delay options, see the <i>Start-Up and Shutdown Delays</i> table.  0h = 0 ms 1h = 1 ms . Fh = 15 ms

### 7.6.1.7 RESET

Address: 0x18

D7	D6	D5	D4	D3	D2	D1	D0

Reserved	SW RESET	
----------	----------	--

Bits	Field	Type	Default	Description
7:1	Reserved	R/W	0h	
0	SW_RESET	R/W		Software commanded reset. When this bit is written to 1h, the registers are reset to the default values, OTP memory is read, and the I <sup>2</sup> C interface is reset. The bit is automatically cleared.



### 7.6.1.8 CONFIG

Address: 0x19

D7	D6	D5	D4	D3	D2	D1	D0
DOUBLE_DEL AY	CLKIN_PD	Reserved	EN3_PD	TDIE_WARN_ LEVEL	EN2_PD	EN1_PD	Reserved

Bits	Field	Type	Default	Description
7	DOUBLE_DELAY	R/W	Х	Start-Up and shutdown delays from the ENx signals 0h = 0 ms to 15 ms with 1-ms steps 1h = 0 ms to 30 ms with 2-ms steps
6	CLKIN_PD	R/W	Х	This bit selects the pulldown resistor on the CLKIN input pin.  0h = Pulldown resistor is disabled  1h = Pulldown resistor is enabled
5	Reserved	R/W	0h	
4	EN3_PD	R/W	Х	This bit selects the pulldown resistor on the EN3 (GPIO3) input pin.  0h = Pulldown resistor is disabled  1h = Pulldown resistor is enabled
3	TDIE_WARN_LEVE L	R/W	Х	Thermal warning threshold level 0h = 125°C 1h = 137°C
2	EN2_PD	R/W	Х	This bit selects the pulldown resistor on the EN2 (GPIO2) input pin.  0h = Pulldown resistor is disabled  1h = Pulldown resistor is enabled
1	EN1_PD	R/W	Х	This bit selects the pulldown resistor on the EN1 (GPIO1) input pin.  0h = Pulldown resistor is disabled  1h = Pulldown resistor is enabled
0	Reserved	R/W	0h	

Submit Document Feedback



## 7.6.1.9 INT\_TOP1

Address: 0x1A

D7	D6	D5	D4	D3	D2	D1	D0
Reserved	INT BUCK23	INT BUCK01	NO SYNC CL	TDIE SD	TDIE WARN	INT OVP	I LOAD READ
	200.120		K K			•	Y

Bits	Field	Туре	Default	Description
7	Reserved	R/W	0h	
6	INT_BUCK23	R	0h	Interrupt indicating that the output of the BUCK3 regulator,BUCK2 regulator, or both regulators has a pending interrupt. The reason for the interrupt is indicated in the INT_BUCK_2_3 register.  This bit is cleared automatically when the INT_BUCK_2_3 register is cleared to 0x00.
5	INT_BUCK01	R	0h	Interrupt indicating that the output of the BUCK1 regulator, BUCK0 regulator, or both regulators has a pending interrupt. The reason for the interrupt is indicated in the INT_BUCK_0_1 register.  This bit is cleared automatically when the INT_BUCK_0_1 register is cleared to 0x00.
4	NO_SYNC_CLK	R/W1C	0h	Latched status bit indicating that the external clock is not valid. Write this bit to 1h to clear the interrupt.
3	TDIE_SD	R/W1C	0h	Latched status bit indicating that the die junction temperature is greater than the thermal shutdown level. The regulators are disabled if previously enabled. The regulators cannot be enabled if this bit is active. The actual status of the thermal warning condition is indicated by the TDIE_SD_STAT bit in the TOP_STAT register. Write this bit to 1h to clear the interrupt.
2	TDIE_WARN	R/W1C	0h	Latched status bit indicating that the die junction temperature is greater than the thermal warning level. The actual status of the thermal warning condition is indicated by the TDIE_WARN_STAT bit in the TOP_STAT register.  Write this bit to 1h to clear the interrupt.
1	INT_OVP	R/W1C	0h	Latched status bit indicating that the input voltage is greater than the overvoltage-detection level. The actual status of the overvoltage condition is indicated by the OVP_STAT bit in the OP_STAT register.  Write this bit to 1h to clear the interrupt.
0	I_LOAD_READY	R/W1C	0h	Latched status bit indicating that the load-current measurement result is available in the I_LOAD_1 and I_LOAD_2 registers.  Write this bit to 1h to clear the interrupt.

## 7.6.1.10 INT\_TOP2

Address: 0x1B

D7	D6	D5	D4	D3	D2	D1	D0
			Reserved				DESET DEC

Bits	Field	Type	Default	Description
7:1	Reserved	R/W	0h	
0	RESET_REG	R/W1C	0h	Latched status bit indicating that either start-up (NRST rising edge) is done, VANA supply voltage is less than the undervoltage threshold level, or the host has requested a reset (the SW_RESET bit in the RESET register). The regulators are disabled, the registers are reset to default values, and the normal start-up procedure is done.  Write this bit to 1h to clear the interrupt.



# 7.6.1.11 INT\_BUCK\_0\_1

Address: 0x1C

D7	D6	D5	D4	D3	D2	D1	D0
Reserved	BUCK1_PG _INT	BUCK1_SC _INT	BUCK1_ILIM _INT	Reserved	BUCK0_PG _INT	BUCK0_SC _INT	BUCK0_ILIM _INT

Bits	Field	Туре	Default	Description
7	Reserved	R/W	0h	
6	BUCK1_PG_INT	R/W1C	0h	Latched status bit indicating that the BUCK1 output voltage reached the power-good-threshold level. Write this bit to 1h to clear.
5	BUCK1_SC_INT	R/W1C	0h	Latched status bit indicating that the BUCK1 output voltage has fallen to less than the 0.35-V level during operation or the BUCK1 output did not reach the 0.35-V level in 1 ms from enable.  Write this bit to 1h to clear.
4	BUCK1_ILIM_INT	R/W1C	0h	Latched status bit indicating that output current limit is active. Write this bit to 1h to clear.
3	Reserved	R/W	0h	
2	BUCK0_PG_INT	R/W1C	0h	Latched status bit indicating that the BUCK0 output voltage reached power-good-threshold level. Write this bit to 1h to clear.
1	BUCK0_SC_INT	R/W1C	0h	Latched status bit indicating that the BUCK0 output voltage has fallen to less than the 0.35-V level during operation or the BUCK0 output did not reach the 0.35-V level in 1 ms from enable.  Write this bit to 1h to clear.
0	BUCK0_ILIM_INT	R/W1C	0h	Latched status bit indicating that output current limit is active. Write this bit to 1h to clear.

Submit Document Feedback



## 7.6.1.12 INT\_BUCK\_2\_3

Address: 0x1D

D7	D6	D5	D4	D3	D2	D1	D0
Reserved	BUCK3_PG _INT	BUCK3_SC _INT	BUCK3_ILIM _INT	Reserved	BUCK2_PG _INT	BUCK2_SC _INT	BUCK2_ILIM _INT

Bits	Field	Туре	Default	Description
7	Reserved	R/W	0h	
6	BUCK3_PG_INT	R/W1C	0h	Latched status bit indicating that the BUCK3 output voltage reached the power-good-threshold level. Write this bit to 1h to clear.
5	BUCK3_SC_INT	R/W1C	0h	Latched status bit indicating that the BUCK3 output voltage has fallen to less than the 0.35-V level during operation or the BUCK3 output did not reach the 0.35-V level in 1 ms from enable.  Write this bit to 1h to clear.
4	BUCK3_ILIM_INT	R/W1C	0h	Latched status bit indicating that the output current limit is active. Write this bit to 1h to clear.
3	Reserved	R/W	0h	
2	BUCK2_PG_INT	R/W1C	0h	Latched status bit indicating that the BUCK2 output voltage reached the power-good-threshold level. Write this bit to 1h to clear.
1	BUCK2_SC_INT	R/W1C	0h	Latched status bit indicating that the BUCK2 output voltage has fallen to less than the 0.35-V level during operation or the BUCK2 output did not reach the 0.35-V level in 1 ms from enable.  Write this bit to 1h to clear.
0	BUCK2_ILIM_INT	R/W1C	0h	Latched status bit indicating that the output current limit is active. Write this bit to 1h to clear.

## 7.6.1.13 TOP\_STAT

Address: 0x1E

D7 D6	D5	D4	D3	D2	D1	D0
Reserve	ed .	SYNC_CLK STAT	TDIE_SD STAT	TDIE_WARN STAT	OVP_STAT	Reserved

Bits	Field	Type	Default	Description
7:5	Reserved	R	0h	
4	SYNC_CLK_STAT	R	0h	Status bit indicating the status of the external clock (CLKIN).  0h = External clock frequency is valid  1h = External clock frequency is not valid
3	TDIE_SD_STAT	R	0h	Status bit indicating the status of the thermal shutdown condition.  0h = Die temperature is less than the thermal shutdown level  1h = Die temperature is greater than the thermal shutdown level
2	TDIE_WARN_STAT	R	0h	Status bit indicating the status of thermal warning condition.  0h = Die temperature is less than the thermal warning level  1h = Die temperature is greater than the thermal warning level
1	OVP_STAT	R	0h	Status bit indicating the status of input overvoltage monitoring.  0h = Input voltage is less than the overvoltage threshold level  1h = Input voltage is greater than the overvoltage threshold level
0	Reserved	R	0h	



# 7.6.1.14 BUCK\_0\_1\_STAT

Address: 0x1F

D7	D6	D5	D4	D3	D2	D1	D0
BUCK1_STAT	BUCK1_PG _STAT	Reserved	BUCK1_ILIM _STAT	BUCK0_STAT	BUCK0_PG _STAT	Reserved	BUCK0_ILIM _STAT

Bits	Field	Type	Default	Description
7	BUCK1_STAT	R	0	Status bit indicating the enable or disable status of the BUCK1 regulator.  0h = BUCK1 regulator is disabled  1h = BUCK1 regulator is enabled
6	BUCK1_PG_STAT	R	0	Status bit indicating the validity of the BUCK1 output voltage (raw status).  0h = BUCK1 output is less than the power-good-threshold level  1h = BUCK1 output is greater than the power-good-threshold level
5	Reserved	R	0	
4	BUCK1_ILIM_STAT	R	0	Status bit indicating the BUCK1 current limit status (raw status).  0h = BUCK1 output current is less than the current limit level  1h = BUCK1 output current limit is active
3	BUCK0_STAT	R	0	Status bit indicating the enable or disable status of the BUCK0 regulator.  0h = BUCK0 regulator is disabled  1h = BUCK0 regulator is enabled
2	BUCK0_PG_STAT	R	0	Status bit indicating the validity of the BUCK0 output voltage (raw status).  0h = BUCK0 output is less than the power-good-threshold level  1h = BUCK0 output is greater than the power-good-threshold level
1	Reserved	R	0	
0	BUCK0_ILIM_STAT	R	0	Status bit indicating the BUCK0 current limit status (raw status).  0h = BUCK0 output current is less than the current limit level 1h = BUCK0 output current limit is active

Submit Document Feedback



## 7.6.1.15 BUCK\_2\_3\_STAT

Address: 0x20

D7	D6	D5	D4	D3	D2	D1	D0
BUCK3_STAT	BUCK3_PG _STAT	Reserved	BUCK3_ILIM _STAT	BUCK2_STAT	BUCK2_PG _STAT	Reserved	BUCK2_ILIM _STAT

Bits	Field	Type	Default	Description		
7	BUCK3_STAT	R	0	Status bit indicating the enable or disable status of the BUCK3 regulator.  0h = BUCK3 regulator is disabled  1h = BUCK3 regulator is enabled		
6	BUCK3_PG_STAT	R	0	Status bit indicating the validity of the BUCK3 output voltage (raw status).  0h = BUCK3 output is less than the power-good-threshold level  1h = BUCK3 output is greater than the power-good-threshold level		
5	Reserved	R	0			
4	BUCK3_ILIM_STAT	R	0	Status bit indicating the BUCK3 current limit status (raw status).  0h = BUCK3 output current is less than the current limit level  1h = BUCK3 output current limit is active		
3	BUCK2_STAT	R	0	Status bit indicating the enable or disable status of the BUCK2 regulator.  0h = BUCK2 regulator is disabled  1h = BUCK2 regulator is enabled		
2	BUCK2_PG_STAT	R	0	Status bit indicating the validity of the BUCK2 output voltage (raw status)  0h = BUCK2 output is less than the power-good-threshold level  1h = BUCK2 output is greater than the power-good-threshold level		
1	Reserved	R	0			
0	BUCK2_ILIM_STAT	R	0	Status bit indicating the BUCK2 current limit status (raw status).  0h = BUCK2 output current is less than the current limit level  1h = BUCK2 output current limit is active		

## 7.6.1.16 TOP\_MASK1

Address: 0x21

D7	D6	D5	D4	D3	D2	D1	D0
Reserved	Rese	erved	SYNC_CLK _MASK	Reserved	TDIE_WARN _MASK	Reserved	I_LOAD_ READY_MASK

Bits	Field	Type	Default	Description
7	Reserved	R/W	1h	
6:5	Reserved	R/W	0h	
4	SYNC_CLK_MASK	R/W	Х	Masking for the external clock detection interrupt (the NO_SYNC_CLK bit in the INT_TOP1 register)  0h = Interrupt generated  1h = Interrupt not generated
3	Reserved	R/W	0h	
2	TDIE_WARN_MAS K	R/W	Х	Masking for the thermal warning interrupt (the TDIE_WARN bit in the INT_TOP1 register) This bit does not affect TDIE_WARN_STAT status bit in the TOP_STAT register. 0h = Interrupt generated 1h = Interrupt not generated
1	Reserved	R/W	0	
0	I_LOAD_READY_M ASK	R/W	X	Masking for the load-current measurement-ready interrupt (the I_LOAD_READY bit in the INT_TOP register).  0h = Interrupt generated 1h = Interrupt not generated



## 7.6.1.17 TOP\_MASK2

Address: 0x22

	D7	D6	D5	D4	D3	D2	D1	D0
Г				Reserved				RESET_REG
								_MASK

Bits	Field	Type	Default	Description
7:1	Reserved	R/W	0h	
0	RESET_REG_MAS K	R/W		Masking for the register reset interrupt (the RESET_REG bit in the INT_TOP2 register)  0h = Interrupt generated 1h = Interrupt not generated

## 7.6.1.18 BUCK\_0\_1\_MASK

Address: 0x23

D7	D6	D5	D4	D3	D2	D1	D0
Reserved	BUCK1_PG _MASK	Reserved	BUCK1_ILIM _MASK	Reserved	BUCK0_PG _MASK	Reserved	BUCK0_ILIM _MASK

Bits	Field	Type	Default	Description
7	Reserved	R/W	0h	
6	BUCK1_PG_MASK	R/W	Х	Masking for the BUCK1 power-good interrupt (the BUCK1_PG_INT bit in the INT_BUCK_0_1 register) This bit does not affect BUCK1_PG_STAT status bit in BUCK_0_1_STAT register. 0h = Interrupt generated 1h = Interrupt not generated
5	Reserved	R	0h	
4	BUCK1_ILIM_MAS K	R/W	Х	Masking for the BUCK1 current-limit-detection interrupt (the BUCK1_ILIM_INT bit in the INT_BUCK_0_1 register) This bit does not affect the BUCK1_ILIM_STAT status bit in the BUCK_0_1_STAT register.  0h = Interrupt generated 1h = Interrupt not generated
3	Reserved	R/W	0h	
2	BUCK0_PG_MASK	R/W	Х	Masking for the BUCK0 power-good interrupt (the BUCK0_PG_INT bit in the INT_BUCK_0_1 register) This bit does not affect the BUCK0_PG_STAT status bit in the BUCK_0_1_STAT register.  0h = Interrupt generated 1h = Interrupt not generated
1	Reserved	R	0h	
0	BUCK0_ILIM_MAS K	R/W	Х	Masking for the BUCK0 current-limit-detection interrupt (the BUCK0_ILIM_INT bit in the INT_BUCK_0_1 register) This bit does not affect the BUCK0_ILIM_STAT status bit in the BUCK_0_1_STAT register.  0h = Interrupt generated 1h = Interrupt not generated

Submit Document Feedback



## 7.6.1.19 BUCK\_2\_3\_MASK

Address: 0x24

D7	D6	D5	D4	D3	D2	D1	D0
Reserved	BUCK3_PG _MASK	Reserved	BUCK3_ILIM _MASK	Reserved	BUCK2_PG _MASK	Reserved	BUCK2_ILIM _MASK

Bits	Field	Туре	Default	Description
7	Reserved	R/W	0h	
6	BUCK3_PG_MASK	R/W	Х	Masking for the BUCK3 power-good interrupt (the BUCK3_PG_INT bit in the INT_BUCK_2_3 register) This bit does not affect the BUCK3_PG_STAT status bit in the BUCK_2_3_STAT register.  0h = Interrupt generated 1h = Interrupt not generated
5	Reserved	R	0h	
4	BUCK3_ILIM_MAS K	R/W	Х	Masking for the BUCK3 current-limit-detection interrupt (the BUCK3_ILIM_INT bit in the INT_BUCK_2_3 register) This bit does not affect the BUCK3_ILIM_STAT status bit in the BUCK_2_3_STAT register.  0h = Interrupt generated 1h = Interrupt not generated
3	Reserved	R/W	0h	
2	BUCK2_PG_MASK	R/W	X	Masking for the BUCK2 power-good interrupt (the BUCK2_PG_INT bit in the INT_BUCK_2_3 register) This bit does not affect the BUCK2_PG_STAT status bit in the BUCK_2_3_STAT register.  0h = Interrupt generated 1h = Interrupt not generated
1	Reserved	R	0h	
0	BUCK2_ILIM_MAS K	R/W	Х	Masking for the BUCK2 current limit-detection interrupt (the BUCK2_ILIM_INT bit in the INT_BUCK_2_3 register) This bit does not affect the BUCK2_ILIM_STAT status bit in the BUCK_2_3_STAT register.  0h = Interrupt generated 1h = Interrupt not generated

## 7.6.1.20 SEL\_I\_LOAD

Address: 0x25

D7	D6	D5	D4	D3	D2	D1	D0
		Rese	erved			LOAD_CUR _SELE	RENT_BUCK CT[1:0]

Bits	Field	Type	Default	Description
7:2	Reserved	R/W	0h	
1:0	LOAD_CURRENT_ BUCK_SELECT[1:0 ]	R/W	Oh	This bit starts the current measurement on the selected regulator.  One measurement is started when the register is written.  If the selected buck is a master, the measurement result is the sum of the current of both the master and slave bucks.  If the selected buck is a slave, the measurement result is the current of the selected slave bucks.  Oh = BUCK0  1h = BUCK1  2h = BUCK2  3h = BUCK3



## 7.6.1.21 I\_LOAD\_2

Address: 0x26

D7	D6	D5	D4	D3	D2	D1	D0

Reserved BUCK\_LOAD\_CURRENT[9:8]

Bits	Field	Type	Default	Description
7:2	Reserved	R	0h	
1:0	BUCK_LOAD_CUR RENT[9:8]	R	0h	This register describes the three MSB bits of the average load current on the selected regulator with a resolution of 20 mA per LSB and maximum code corresponding to a 20.47-A current.

## 7.6.1.22 I\_LOAD\_1

Address: 0x27

D7 D6 D5 D4 D3 D2 D1 D0
-------------------------

### BUCK\_LOAD\_CURRENT[7:0]

Bits	Field	Type	Default	Description
7:0	BUCK_LOAD_CUR RENT[7:0]	R	0x00	This register describes the eight LSB bits of the average load current on the selected regulator with a resolution of 20 mA per LSB and maximum code corresponding to a 20.47-A current.

## 7.6.1.23 PGOOD\_CTRL1

Address: 0x28

D7	D6	D5	D4	D3	D2	D1	D0
PG3_S	EL[1:0]	PG2_S	EL[1:0]	PG1_S	EL[1:0]	PG0_S	EL[1:0]

Bits	Field	Type	Default	Description
7:6	PG3_SEL[1:0]	R/W	Х	PGOOD signal source control from the BUCK3 regulator  0h = Masked  1h = Power-good-threshold voltage  2h = Reserved, do not use  3h = Power-good-threshold voltage AND current limit
5:4	PG2_SEL[1:0]	R/W	X	PGOOD signal source control from the BUCK2 regulator 0h = Masked 1h = Power-good-threshold voltage 2h = Reserved, do not use 3h = Power-good threshold voltage AND current limit
3:2	PG1_SEL[1:0]	R/W	Х	PGOOD signal source control from the BUCK1 regulator  0h = Masked  1h = Power-good-threshold voltage  2h = Reserved, do not use  3h = Power-good-threshold voltage AND current limit
1:0	PG0_SEL[1:0]	R/W	Х	PGOOD signal source control from the BUCK0 regulator  0h = Masked  1h = Power-good-threshold voltage  2h = Reserved, do not use  3h = Power-good-threshold voltage AND current limit

Submit Document Feedback



## 7.6.1.24 PGOOD\_CTRL2

Address: 0x29

D7	D6	D5	D4	D3	D2	D1	D0
HALF_DELAY	EN_PG0 _NINT	PGOOD_SET _DELAY	EN_PGFLT _STAT	Reserved	PGOOD_ WINDOW	PGOOD_OD	PGOOD_POL

Bits	Field	Type	Default	Description
7	HALF_DELAY	R/W	Х	This bit elects the time step for the start-up and shutdown delays.  0h = Start-Up and shutdown delays have 0.5-ms or 1-ms time steps, based on the DOUBLE_DELAY bit in the CONFIG register.  1h = Start-Up and shutdown delays have 0.32-ms or 0.64-ms time steps, based on the DOUBLE_DELAY bit in the CONFIG register.
6	EN_PG0_NINT	R/W	Х	This bit combines theBUCK0 PGOOD signal with the nINT signal 0h = BUCK0 PGOOD signal not included with the nINT signal 1h = BUCK0 PGOOD signal included with the nINT signal. If the nINT OR the BUCK0 PGOOD signal is low then the nINT signal is low.
5	PGOOD_SET_DEL AY	R/W	Х	Debounce time of the output voltage monitoring for the PGOOD signal (only when the PGOOD signal goes valid) 0h = 4-10 $\mu$ s 1h = 11 ms
4	EN_PGFLT_STAT	R/W	Х	Operation mode for PGOOD signal 0h = Indicates live status of monitored voltage outputs 1h = Indicates status of the PGOOD_FLT register, inactive if at least one of the PGx_FLT bit is inactive
3	Reserved	R/W	0h	
2	PGOOD_WINDOW	R/W	Х	Voltage monitoring method for the PGOOD signal 0h = Only undervoltage monitoring 1h = Overvoltage and undervoltage monitoring
1	PGOOD_OD	R/W	Х	PGOOD signal type 0h = Push-pull output (VANA level) 1h = Open-drain output
0	PGOOD_POL	R/W	Х	PGOOD signal polarity 0h = PGOOD signal high when monitored outputs are valid 1h = PGOOD signal low when monitored outputs are valid



## 7.6.1.25 PGOOD\_FLT

Address: 0x2A

D7	D6	D5	D4	D3	D2	D1	D0
	Rese	erved		PG3_FLT	PG2_FLT	PG1_FLT	PG0_FLT

Bits	Field	Type	Default	Description
7:4	Reserved	R/W	0x0	
3	PG3_FLT	R	0	Source for the PGOOD inactive signal  0h = BUCK3 has not set the PGOOD signal inactive.  1h = BUCK3 has set the PGOOD signal inactive. This bit can be cleared by reading this register when the BUCK3 output is valid.
2	PG2_FLT	R	0	Source for the PGOOD inactive signal 0h = BUCK2 has not set the PGOOD signal inactive. 1h = BUCK2 has set the PGOOD signal inactive. This bit can be cleared by reading this register when the BUCK2 output is valid.
1	PG1_FLT	R	0	Source for the PGOOD inactive signal 0h = BUCK1 has not set the PGOOD signal inactive. 1h = BUCK1 has set the PGOOD signal inactive. This bit can be cleared by reading this register when the BUCK1 output is valid.
0	PG0_FLT	R	0	Source for the PGOOD inactive signal 0h = BUCK0 has not set the PGOOD signal inactive. 1h = BUCK0 has set the PGOOD signal inactive. This bit can be cleared by reading this register when the BUCK0 output is valid.

### 7.6.1.26 PLL\_CTRL

Address: 0x2B

D/	D6	D5	D4	D3	D2	D1	D0
PLL_MC	DDE[1:0]	Reserved		EX	T_CLK_FREQ[4	:0]	

Bits	Field	Type	Default	Description
7:6	PLL_MODE[1:0]	R/W	X	This bit selects the external clock and PLL operation.  0h = Forced to internal RC oscillator (PLL is disabled).  1h = PLL is enabled in the STANDBY and ACTIVE states. Automatic external clock use when available, interrupt generated if external clock appears or disappears.  2h = PLL is enabled only in the ACTIVE state. Automatic external clock use when available, interrupt generated if external clock appears or disappears.  3h = Reserved
5	Reserved	R/W	0	
4:0	EXT_CLK_FREQ[4: 0]	R/W	х	Frequency of the external clock (CLKIN). For the input clock frequency tolerance see the <i>Electrical Characteristics</i> table. Settings 18h through 1Fh are reserved and must not be used.  0x00h = 1 MHz  0x01h = 2 MHz  2h = 3 MHz  16h = 23 MHz  17h = 24 MHz.

Submit Document Feedback



## 7.6.1.27 PIN\_FUNCTION

Address: 0x2C

D7	D6	D5	D4	D3	D2	D1	D0
EN_SPREAD_ SPEC	EN_PIN_CTRL _GPIO3	EN_PIN_SELE CT_GPIO3	EN_PIN_CTRL _GPIO2	EN_PIN_SELE CT_GPIO2	GPIO3_SEL	GPIO2_SEL	GPIO1_SEL

Bits	Field	Туре	Default	Description				
7	EN_SPREAD_SPE C	R/W	Х	This bit enables the spread-spectrum feature.  0h = Disabled 1h = Enabled				
6	EN_PIN_CTRL_GPI O3	R/W	Х	This bit enables EN1 and EN2 pin control for GPIO3 (the GPIO3_SEL bit is set to 1h AND the GPIO3_DIR bit is set to 1h).  0h = Only GPIO3_OUT bit controls GPIO3  1h = GPIO3_OUT bit AND ENx pin control GPIO3				
5	EN_PIN_SELECT_ GPIO3	R/W	Х	This bit enables EN1 and EN2 pin control for GPIO3.  0h = GPIO3_SEL bit AND EN1 pin control GPIO3  1h = GPIO3_SEL bit AND EN2 pin control GPIO3				
4	EN_PIN_CTRL_GPI O2	R/W	Х	This bit enables EN1 and EN3 pin control for GPIO2 (the GPIO2_SEL bit is set to 1h AND the GPIO2_DIR bit is set to 1h).  0h = Only GPIO2_OUT bit controls GPIO2  1h = GPIO2_OUT bit AND ENx pin control GPIO2				
3	EN_PIN_SELECT_ GPIO2	R/W	Х	This bit enables EN1 and EN3 pin control for GPIO2  0h = GPIO2_SEL bit AND EN1 pin control GPIO2  1h = GPIO2_SEL bit AND EN3 pin control GPIO2				
2	GPIO3_SEL	R/W	Х	This bit selects the EN3 pin function 0h = EN3 1h = GPIO3				
1	GPIO2_SEL	R/W	Х	This bit selects the EN2 pin function  0h = EN2  1h = GPIO2				
0	GPIO1_SEL	R/W	Х	This bit selects the EN1 pin function  0h = EN1  1h = GPIO1				



## 7.6.1.28 GPIO\_CONFIG

Address: 0x2D

D7	D6	D5	D4	D3	D2	D1	D0
Reserved	GPIO3_OD	GPIO2_OD	GPIO1_OD	Reserved	GPIO3_DIR	GPIO2_DIR	GPIO1_DIR

Bits	Field	Туре	Default	Description
7	Reserved	R	0h	
6	GPIO3_OD	R/W	Х	GPIO3 signal type when configured as an output  0h = Push-pull output (VANA level)  1h = Open-drain output
5	GPIO2_OD	R/W	Х	GPIO2 signal type when configured as an output  0h = Push-pull output (VANA level)  1h = Open-drain output
4	GPIO1_OD	R/W	Х	GPIO1 signal type when configured as an output 0h = Push-pull output (VANA level) 1h = Open-drain output
3	Reserved	R	0h	
2	GPIO3_DIR	R/W	Х	GPIO3 signal direction 0h = Input 1h = Output
1	GPIO2_DIR	R/W	Х	GPIO2 signal direction 0h = Input 1h = Output
0	GPIO1_DIR	R/W	Х	GPIO1 signal direction 0h = Input 1h = Output

# 7.6.1.29 GPIO\_IN

Address: 0x2E

	D7	D6	D5	D4	D3	D2	D1	D0
Reserved						GPIO3_IN	GPIO2_IN	GPIO1_IN

Bits	Field	Type	Default	Description
7:3	Reserved	R	0h	
2	GPIO3_IN	R	0h	State of the GPIO3 signal 0h = Logic-low level 1h = Logic high level
1	GPIO2_IN	R	0h	State of the GPIO2 signal 0h = Logic-low level 1h = Logic-high level
0	GPIO1_IN	R	0h	State of the GPIO1 signal 0h = Logic-low level 1h = Logic-high level

Submit Document Feedback



# 7.6.1.30 GPIO\_OUT

Address: 0x2F

D7	7 D6 D5		D4	D3	D2	D1	D0
		Reserved		GPIO3_OUT	GPIO2_OUT	GPIO1_OUT	

Bits	Field	Type	Default	Description
7:3	Reserved	R/W	0h	
2	GPIO3_OUT	R/W	Х	Control for theGPIO3 signal when configured as the GPIO output 0h = Logic-low level 1h = Logic-high level
1	GPIO2_OUT	R/W	Х	Control for the GPIO2 signal when configured as the GPIO output 0h = Logic-low level 1h = Logic-high level
0	GPIO1_OUT	R/W	0h	Control for theGPIO1 signal when configured as the GPIO output 0h = Logic-low level 1h = Logic-high level

### 8 Application and Implementation

#### 备注

以下应用部分中的信息不属于 TI 器件规格的范围, TI 不担保其准确性和完整性。TI 的客户应负责确定器件是否适用于其应用。客户应验证并测试其设计,以确保系统功能。

### 8.1 Application Information

The LP875701-Q1 is a multiphase step-down converter with four switcher cores, which is configured as a single output 4-phase regulator.

### 8.2 Typical Application

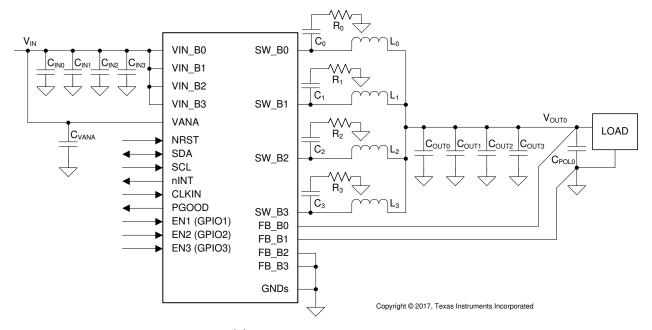


图 8-1. 4-Phase Configuration

#### 8.2.1 Design Requirements

#### 8.2.1.1 Inductor Selection

The inductors are  $L_0$ ,  $L_1$ ,  $L_2$ , and  $L_3$  are shown in #8.2. The inductance and DCR of the inductor affects the control loop of the buck regulator. TI recommends using inductors similar to those listed in  $\frac{1}{8}$  8-1. Pay attention to the saturation current and temperature rise current of the inductor. Check that the saturation current is higher than the peak current limit and the temperature rise current is higher than the maximum expected rms output current. The minimum effective inductance to make sure performance is good is 0.22  $\mu$ H at maximum peak output current over the operating temperature range. DC resistance of the inductor must be less than 0.05  $\Omega$  for good efficiency at high-current condition. The inductor AC loss (resistance) also affects conversion efficiency. Higher Q factor at switching frequency usually gives better efficiency at light load to middle load. Shielded inductors are preferred as they radiate less noise.

Submit Document Feedback

#### 表 8-1. Recommended Inductors

MANUFACTURER	PART NUMBER	VALUE	DIMENSIONS L × W × H (mm)	RATED DC CURRENT, I <sub>SAT</sub> maximum (typical) / I <sub>TEMP</sub> maximum (typical) (A)	DCR typical / maximum (mΩ)
Murata	DFE252012PD-R33M	0.33 µH (20%)	2.5 × 2 × 1.2	6.0 ( - ) / 4.6 ( - ) <sup>(1)</sup>	- / 23

<sup>(1)</sup> Operating temperature range is up to 125°C including self temperature rise.

#### 8.2.1.2 Input Capacitor Selection

The input capacitors  $C_{IN0}$ ,  $C_{IN1}$ ,  $C_{IN2}$ , and  $C_{IN3}$  are shown in #8.2. A ceramic input bypass capacitor of 10  $\,^{\mu}$ F is required for each phase of the regulator. Place the input capacitor as close as possible to the VIN\_Bx pin and PGND\_Bx pin of the device. A larger value or higher voltage rating improves the input voltage filtering. Use X7R type of capacitors, not Y5V or F. DC bias characteristics capacitors must be considered. The minimum effective input capacitance to make sure performance is good is 1.9  $\,^{\mu}$ F for each buck input at the maximum input voltage including tolerances and ambient temperature range. This value assumes that at least 22  $\,^{\mu}$ F of additional capacitance is common for all the power input pins on the system power rail. See  $\gtrsim$  8-2.

The input filter capacitor supplies current to the high-side FET switch in the first half of each cycle and decreases voltage ripple imposed on the input power source. A ceramic capacitor's low ESR provides the best noise filtering of the input voltage spikes due to this rapidly changing current. Select an input filter capacitor with sufficient ripple current rating. In addition ferrite can be used in front of the input capacitor to decrease the EMI.

表 8-2. Recommended Input Capacitors (X7R Dielectric)

MANUFACTURER	PART NUMBER	VALUE	CASE SIZE	DIMENSIONS L × W × H (mm)	VOLTAGE RATING (V)
Murata	GCM21BR71A106KE22	10 μF (10%)	0805	2 × 1.25 × 1.25	10 V

#### 8.2.1.3 Output Capacitor Selection

The output capacitors  $C_{OUT0}$ ,  $C_{OUT1}$ ,  $C_{OUT2}$ , and  $C_{OUT3}$  are shown in  $\dagger$  8.2. A ceramic local output capacitor of 22  $\mu$  F is required per phase. Use ceramic capacitors, X7R or X7T types; do not use Y5V or F. DC bias voltage characteristics of ceramic capacitors must be considered. The output filter capacitor smooths out current flow from the inductor to the load, helps keep a steady output voltage during transient load changes and decreases output voltage ripple. These capacitors must be selected with sufficient capacitance and sufficiently low ESR and ESL to do these functions. The minimum effective output capacitance to make sure performance is good is 10  $\mu$  F for each phase including the DC voltage roll-off, tolerances, aging and temperature effects.

The output voltage ripple is caused by the charging and discharging of the output capacitor and also due to its  $R_{ESR}$ . The  $R_{ESR}$  is frequency dependent (as well as temperature dependent); make sure the value used for selection process is at the switching frequency of the part. See  $\frac{1}{8}$  8-3.

POL capacitor ( $C_{POL0}$ ) needs to be used to maintain output voltage stability and improve load transient performance and to decrease the ripple voltage. Note that the output capacitor may be the limiting factor in the output voltage ramp and the maximum total output capacitance listed in electrical characteristics must not be exceeded. At shutdown the output voltage is discharged to 0.6 V level using forced-PWM operation. This can increase the input voltage if the load current is small and the output capacitor is large. Below 0.6 V level the output capacitor is discharged by the internal discharge resistor and with large capacitor more time is required to settle  $V_{OUT}$  down as a consequence of the increased time constant.



### 表 8-3. Recommended Output Capacitors (X7R or X7T Dielectric)

MANUFACTURER	PART NUMBER	VALUE	CASE SIZE	DIMENSIONS L × W × H (mm)	VOLTAGE RATING (V)
Murata	GCM31CR71A226KE02	22 μF (10%)	1206	3.2 × 1.6 × 1.6	10

#### 8.2.1.4 Snubber Components

If the input voltage for the regulators is above 4 V, snubber components are needed at the switching nodes to decrease voltage spiking in the switching node and to improve EMI. The snubber capacitors  $C_0$ ,  $C_1$ ,  $C_2$ , and  $C_3$  and the snubber resistors  $R_0$ ,  $R_1$ ,  $R_2$ , and  $R_3$  are shown in 8 8-1. The recommended components are shown in 8 8-4 and these component values give good performance on LP875701-Q1 EVM. The optimal resistance and capacitance values finally depend on the PCB layout.

### 表 8-4. Recommended Snubber Components

MANUFACTURER	PART NUMBER	VALUE	CASE SIZE	DIMENSIONS L × W x H (mm)	VOLTAGE / POWER RATING
Vishay-Dale	CRCW04023R90JNED	3.9 Ω (5%)	0402	1 × 0.5 × 0.4	62 mW
Murata	GCM1555C1H391JA16	390 pF (5%)	0402	1 × 0.5 × 0.5	50 V

#### 8.2.1.5 Supply Filtering Components

The VANA input is used to supply analog and digital circuits in the device. See 表 8-5 for recommended components for VANA input supply filtering.

表 8-5. Recommended Supply Filtering Components

MANUFACTURER	PART NUMBER	VALUE	CASE SIZE	DIMENSIONS L × W × H (mm)	VOLTAGE RATING (V)
Murata	GCM155R71C104KA55	100 nF (10%)	0402	1.0 × 0.5 × 0.5	16
Murata	GCM188R71C104KA37	100 nF (10%)	0603	1.6 × 0.8 × 0.8	16

### 8.2.2 Detailed Design Procedure

The performance of the LP875701-Q1 device depends greatly on the care taken in designing the printed circuit board (PCB). The use of low-inductance and low serial-resistance ceramic capacitors is strongly recommended, while correct grounding is crucial. Attention must be given to decoupling the power supplies. Decoupling capacitors must be connected close to the device and between the power and ground pins to support high peak currents being drawn from system power rail during turnon of the switching MOSFETs. Keep input and output traces as short as possible, because trace inductance, resistance, and capacitance can easily become the performance limiting items. The separate power pins VIN\_Bx are not connected together internally. Connect the VIN\_Bx power connections together outside the package using power plane construction.

Submit Document Feedback



### 8.2.3 Application Curves

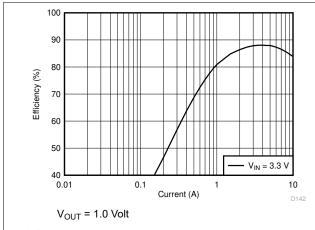


图 8-2. Efficiency in Forced-PWM-Four-Phase mode

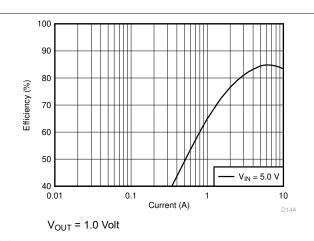


图 8-3. Efficiency in Forced-PWM-Four-Phase Mode

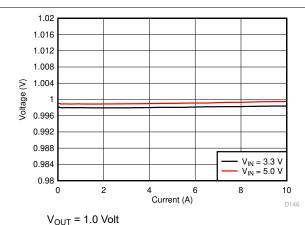
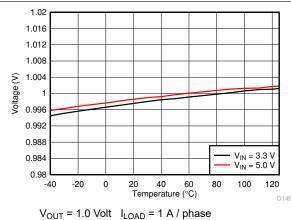


图 8-4. Output Voltage vs Load Current in Forced-PWM-Four-Phase Mode



 $V_{OUT}$  = 1.0 Volt  $I_{LOAD}$  = 1 A / phase (4 A total)

#### 图 8-5. Output Voltage vs Temperature

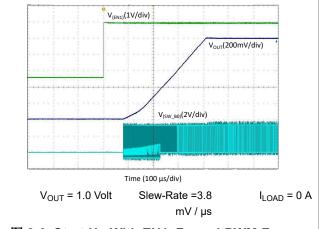


图 8-6. Start-Up With EN1, Forced-PWM-Four-Phase Mode

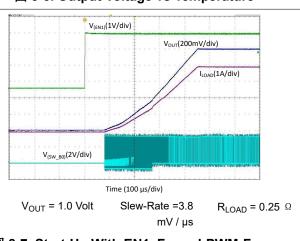
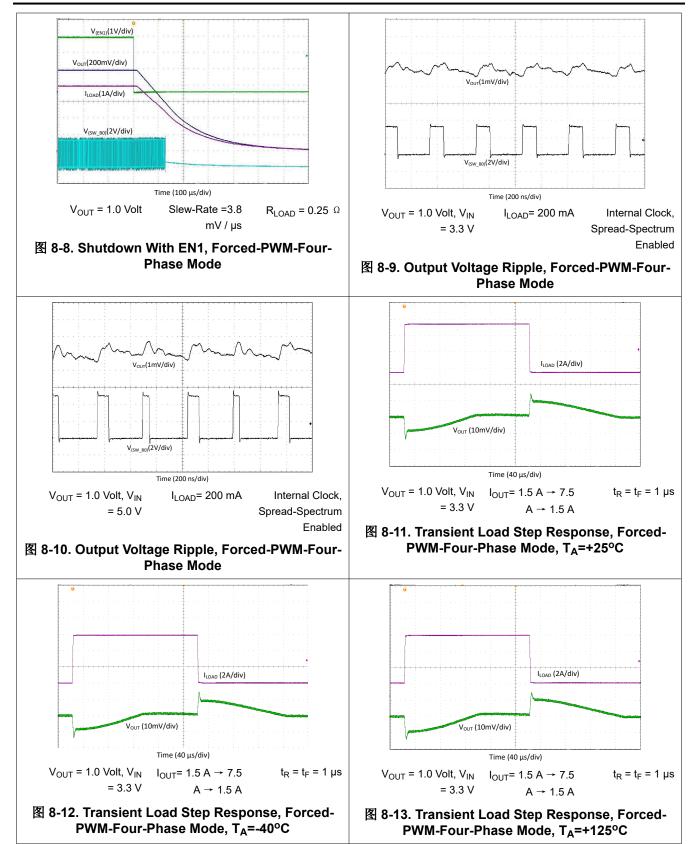
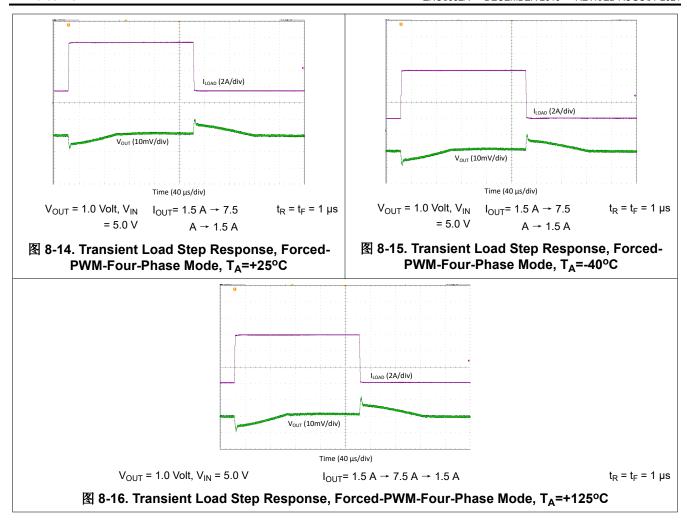


图 8-7. Start-Up With EN1, Forced-PWM-Four-Phase Mode







### 9 Power Supply Recommendations

The device is designed to operate from an input voltage supply range from 2.8 V and 5.5 V. This input supply must be well regulated and can withstand maximum input current and keep a stable voltage without voltage drop even at load transition condition. The resistance of the input supply rail must be low enough that the input current transient does not cause too high drop in the LP875701-Q1 supply voltage that can cause false UVLO fault triggering. If the input supply is located more than a few inches from the LP875701-Q1 additional bulk capacitance may be required in addition to the ceramic bypass capacitors.

### 10 Layout

### 10.1 Layout Guidelines

The high frequency and large switching currents of the LP875701-Q1 make the choice of layout important. Good power supply results only occur when care is given to correct design and layout. Layout affects noise pickup and generation and can cause a good design to perform with less-than-expected results. With a range of output currents from milliamps to 10 A and over, good power supply layout is much more difficult than most general PCB design. Use the following steps as a reference to make sure the device is stable and keeps correct voltage and current regulation across its intended operating voltage and current range.

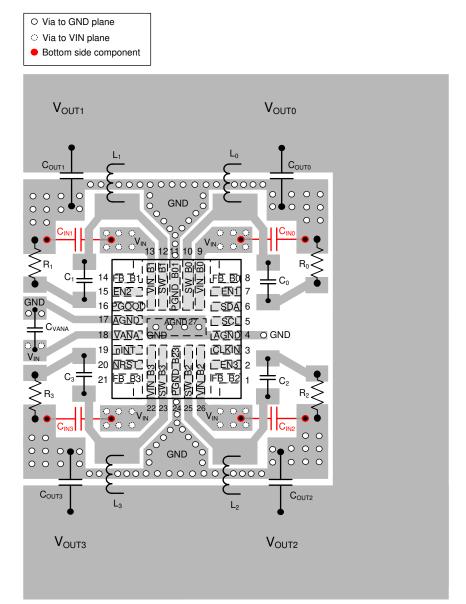
- Place C<sub>IN</sub> as close as possible to the VIN\_Bx pin and the PGND\_Bxx pin. Route the V<sub>IN</sub> trace wide and thick to avoid IR drops. The trace between the positive node of the input capacitor and the VIN\_Bx pin(s) of LP875701-Q1, as well as the trace between the negative node of the input capacitor and power PGND\_Bxx pin(s), must be kept as short as possible. The input capacitance provides a low-impedance voltage source for the switching converter. The inductance of the connection is the most important parameter of a local decoupling capacitor parasitic inductance on these traces must be kept as small as possible for correct device operation. The parasitic inductance can be decreased by using a ground plane as close as possible to top layer by using thin dielectric layer between top layer and ground plane.
- The output filter, consisting of COUT and L, converts the switching signal at SW\_Bx to the noiseless output voltage. It must be placed as close as possible to the device keeping the switch node small, for best EMI behavior. Route the traces between the LP875701-Q1 output capacitors and the load direct and wide to avoid losses due to the IR drop.
- Input for analog blocks (VANA and AGND) must be isolated from noisy signals. Connect VANA directly to a
  quiet system voltage node and AGND to a quiet ground point where no IR drop occurs. Place the decoupling
  capacitor as close as possible to the VANA pin.
- If the processor load supports remote voltage sensing, connect the feedback pins FB\_Bx of the LP875701-Q1 device to the respective sense pins on the processor. The sense lines are susceptible to noise. They must be kept away from noisy signals such as PGND\_Bxx, VIN\_Bx, and SW\_Bx, as well as high bandwidth signals such as the I²C. Avoid both capacitive and inductive coupling by keeping the sense lines short, direct, and close to each other. Run the lines in a quiet layer. Isolate them from noisy signals by a voltage or ground plane if possible. Running the signal as a differential pair is recommended for multiphase outputs. If series resistors are used for load current measurement, place them after connection of the voltage feedback. Connect feedback pin FB\_B0 to supply terminal of the point-of-load, and feedback pin FB\_B1 to the GND of the point-of-load.
- PGND\_Bxx, VIN\_Bx and SW\_Bx must be routed on thick layers. They must not surround inner signal layers, which are cannot withstand interference from noisy PGND\_Bxx, VIN\_Bx and SW\_Bx.
- If the input voltage is above 4 V, place snubber components (capacitor and resistor) between SW\_Bx and ground on all four phases. The components can be also placed to the other side of the board if there are area limitations and the routing traces can be kept short.

Due to the small package of this converter and the overall small solution size, the thermal performance of the PCB layout is important. Many system-dependent parameters such as thermal coupling, airflow, added heat sinks and convection surfaces, and the presence of other heat-generating components affect the power dissipation limits of a given component. Correct PCB layout, focusing on thermal performance, results in lower die temperatures. Wide and thick power traces can sink dissipated heat. This can be improved further on multilayer PCB designs with vias to different planes. This results in decreased junction-to-ambient (R  $_{\theta \text{ JA}}$ ) and junction-to-board (R  $_{\theta \text{ JB}}$ ) thermal resistances and thereby decreases the device junction temperature, T $_{\text{J}}$ . TI strongly recommends doing a careful system-level 2D or full 3D dynamic thermal analysis at the beginning product design process, by using a thermal modeling analysis software.

Submit Document Feedback

### 10.2 Layout Example

Below example is an illustrative example only. For an exact PCB layout example, please refer to the EVM Manual



A. The output voltage rails are shorted together based on the configuration as shown in # 8.2.

图 10-1. Board Layout

### 11 Device and Documentation Support

### 11.1 接收文档更新通知

要接收文档更新通知,请导航至 ti.com 上的器件产品文件夹。点击*订阅更新* 进行注册,即可每周接收产品信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

### 11.2 支持资源

TI E2E™ 支持论坛是工程师的重要参考资料,可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者"按原样"提供。这些内容并不构成 TI 技术规范,并且不一定反映 TI 的观点;请参阅 TI 的《使用条款》。

#### 11.3 Trademarks

TI E2E<sup>™</sup> is a trademark of Texas Instruments.

所有商标均为其各自所有者的财产。

#### 11.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 11.5 术语表

TI术语表本术语表列出并解释了术语、首字母缩略词和定义。

### 12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Submit Document Feedback

### 重要声明和免责声明

TI 提供技术和可靠性数据(包括数据表)、设计资源(包括参考设计)、应用或其他设计建议、网络工具、安全信息和其他资源,不保证没有瑕疵且不做出任何明示或暗示的担保,包括但不限于对适销性、某特定用途方面的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将自行承担以下全部责任:(1) 针对您的应用选择合适的 TI 产品,(2) 设计、验证并测试您的应用,(3) 确保您的应用满足相应标准以及任何其他安全、安保或其他要求。这些资源如有变更,恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的应用。严禁对这些资源进行其他复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。您应全额赔偿因在这些资源的使用中对 TI 及其代表造成的任何索赔、损害、成本、损失和债务,TI 对此概不负责。

TI 提供的产品受 TI 的销售条款 (https://www.ti.com/legal/termsofsale.html) 或 ti.com 上其他适用条款/TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。

邮寄地址:Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2021,德州仪器 (TI) 公司 www.ti.com 4-Feb-2022

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
LP875701ARNFRQ1	ACTIVE	VQFN-HR	RNF	26	3000	RoHS-Exempt & Green	SN	Level-1-260C-UNLIM	-40 to 125	LP8757 01A-Q1	Samples
LP875701ARNFTQ1	ACTIVE	VQFN-HR	RNF	26	250	RoHS-Exempt & Green	SN	Level-1-260C-UNLIM	-40 to 125	LP8757 01A-Q1	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.



## **PACKAGE OPTION ADDENDUM**

www.ti.com 4-Feb-2022

## PACKAGE MATERIALS INFORMATION

www.ti.com 4-Feb-2022

### TAPE AND REEL INFORMATION





A0	
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

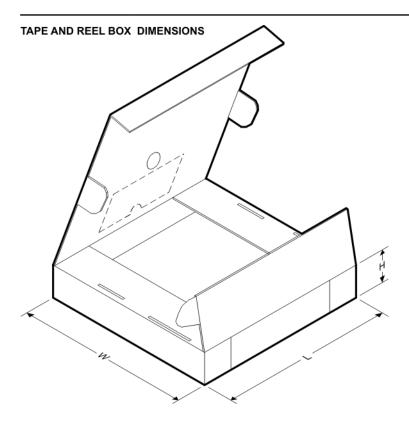


#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LP875701ARNFRQ1	VQFN- HR	RNF	26	3000	330.0	12.4	4.25	4.75	1.2	8.0	12.0	Q1
LP875701ARNFTQ1	VQFN- HR	RNF	26	250	180.0	12.4	4.25	4.75	1.2	8.0	12.0	Q1

**PACKAGE MATERIALS INFORMATION** 

www.ti.com 4-Feb-2022

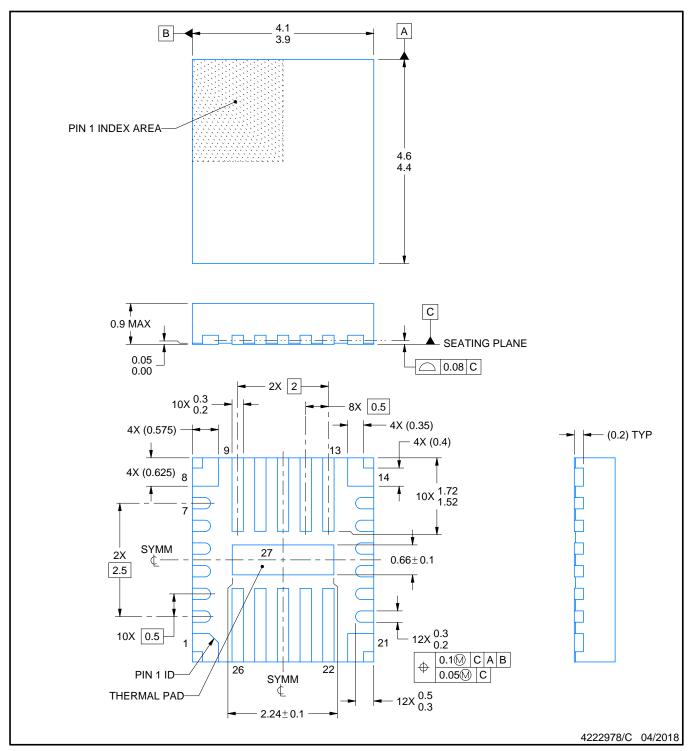


#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LP875701ARNFRQ1	VQFN-HR	RNF	26	3000	346.0	346.0	35.0
LP875701ARNFTQ1	VQFN-HR	RNF	26	250	200.0	183.0	25.0



PLASTIC QUAD FLATPACK - NO LEAD

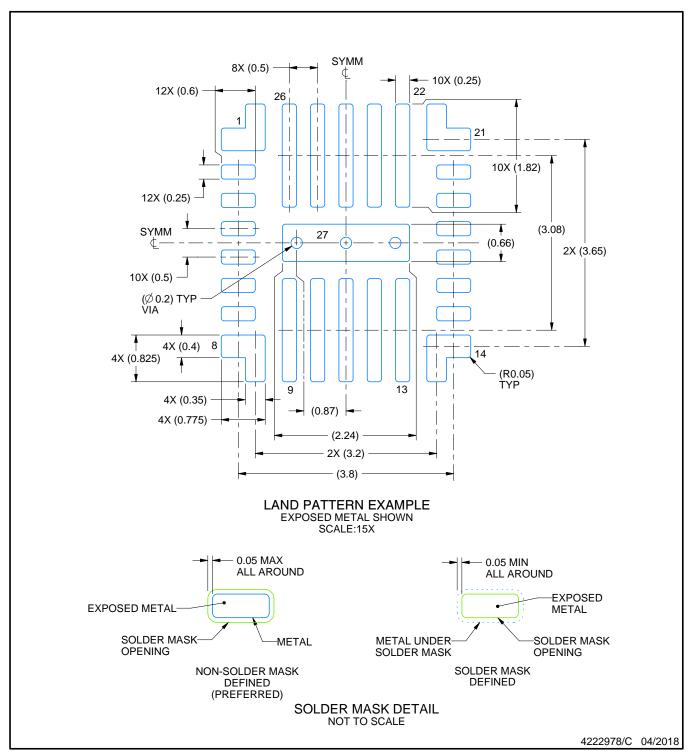


#### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
   This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

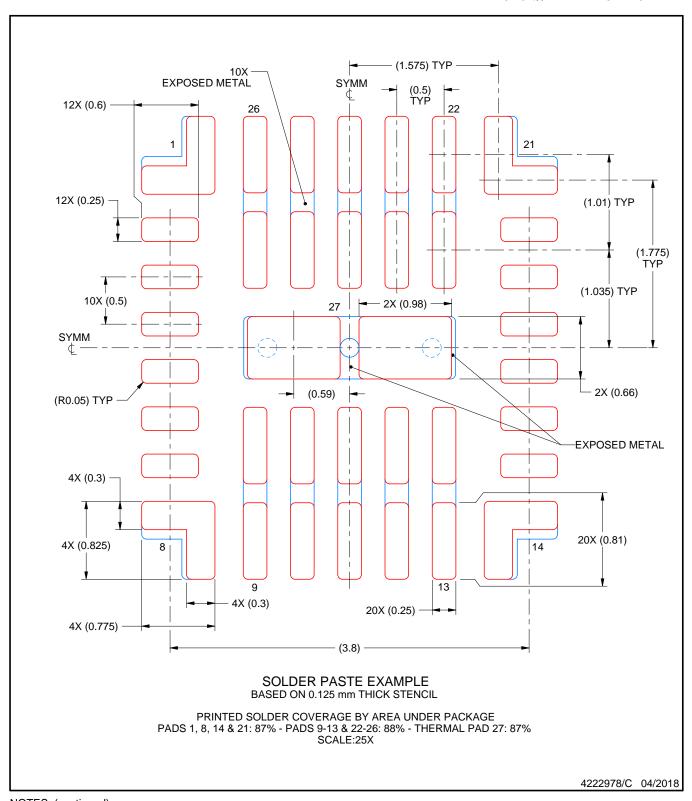


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. For alternate stencil design recommendations, see IPC-7525 or board assembly site preference.



### 重要声明和免责声明

TI"按原样"提供技术和可靠性数据(包括数据表)、设计资源(包括参考设计)、应用或其他设计建议、网络工具、安全信息和其他资源,不保证没有瑕疵且不做出任何明示或暗示的担保,包括但不限于对适销性、某特定用途方面的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将自行承担以下全部责任:(1) 针对您的应用选择合适的 TI 产品,(2) 设计、验证并测试您的应用,(3) 确保您的应用满足相应标准以及任何其他功能安全、信息安全、监管或其他要求。

这些资源如有变更,恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的应用。严禁对这些资源进行其他复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。您应全额赔偿因在这些资源的使用中对 TI 及其代表造成的任何索赔、损害、成本、损失和债务,TI 对此概不负责。

TI 提供的产品受 TI 的销售条款或 ti.com 上其他适用条款/TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。

TI 反对并拒绝您可能提出的任何其他或不同的条款。

邮寄地址:Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2022,德州仪器 (TI) 公司